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(54) **METHODS OF PERFORMING FIN CUT ETCH PROCESSES FOR FINFET SEMICONDUCTOR DEVICES**

H01L 29/0847 (2013.01); *H01L 29/66545* (2013.01); *H01L 27/1104* (2013.01); *H01L 29/7848* (2013.01)

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H01L 27/092 (2006.01)
H01L 29/06 (2006.01)
H01L 29/08 (2006.01)
H01L 29/66 (2006.01)
H01L 21/8234 (2006.01)
H01L 29/78 (2006.01)
H01L 27/11 (2006.01)

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CPC *H01L 21/823821* (2013.01); *H01L 21/823481* (2013.01); *H01L 21/823814* (2013.01); *H01L 21/823878* (2013.01); *H01L 27/0924* (2013.01); *H01L 29/0653* (2013.01);

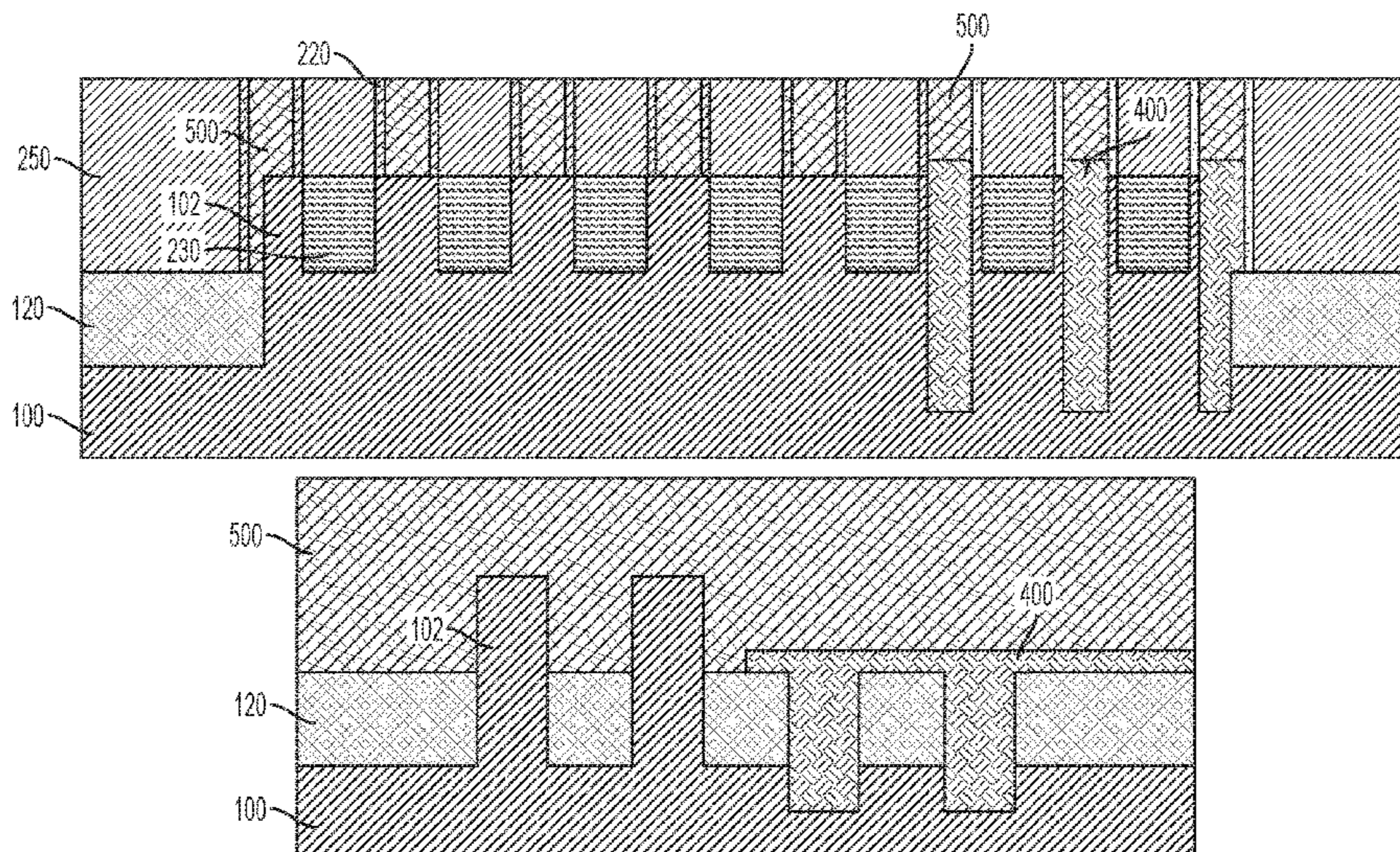
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USPC 257/401, 368, E21.409, E27.06; 438/296
See application file for complete search history.

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(57) **ABSTRACT**
In a self-aligned fin cut process for fabricating integrated circuits, a sacrificial gate or an epitaxially-formed source/drain region is used as an etch mask in conjunction with a fin cut etch step to remove unwanted portions of the fins. The process eliminates use of a lithographically-defined etch mask to cut the fins, which enables precise and accurate alignment of the fin cut.

20 Claims, 21 Drawing Sheets



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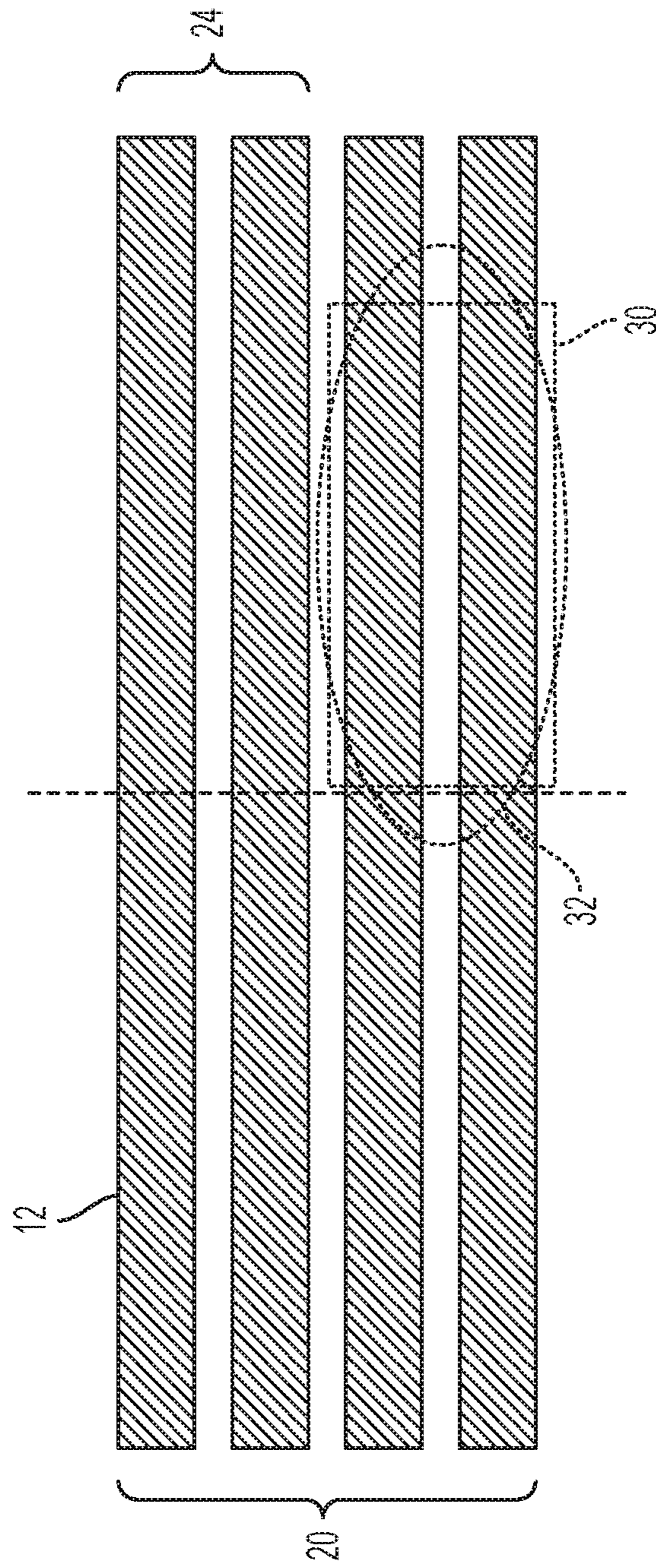


FIG. 1
PRIOR ART

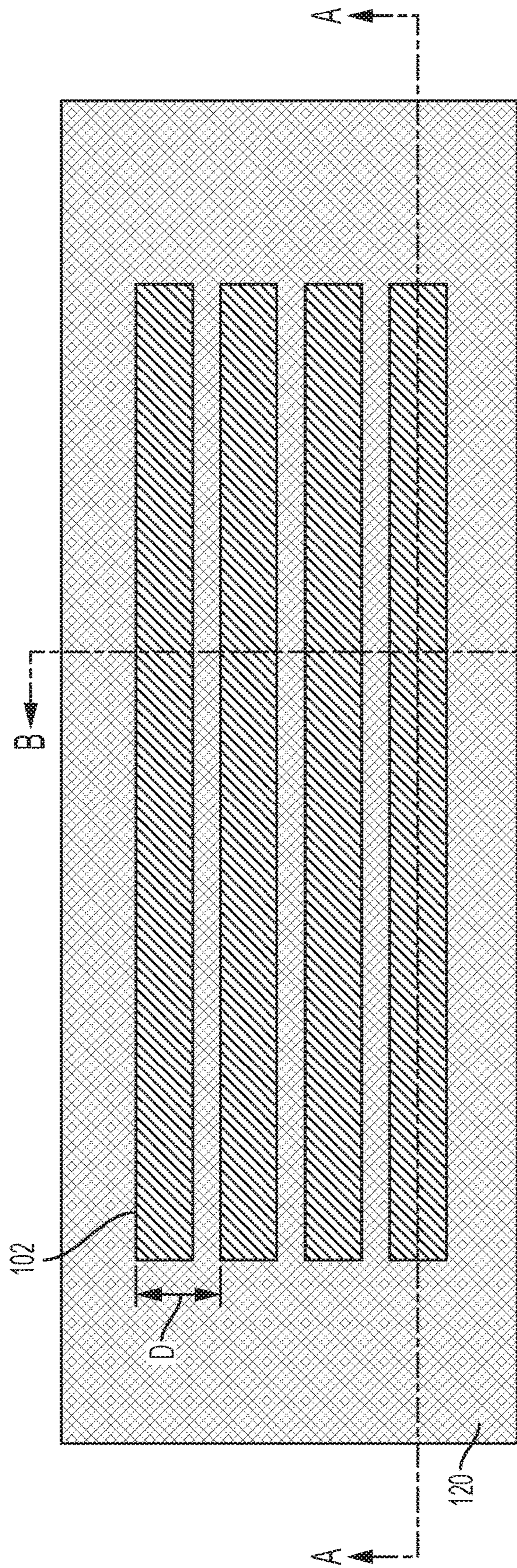


FIG. 2

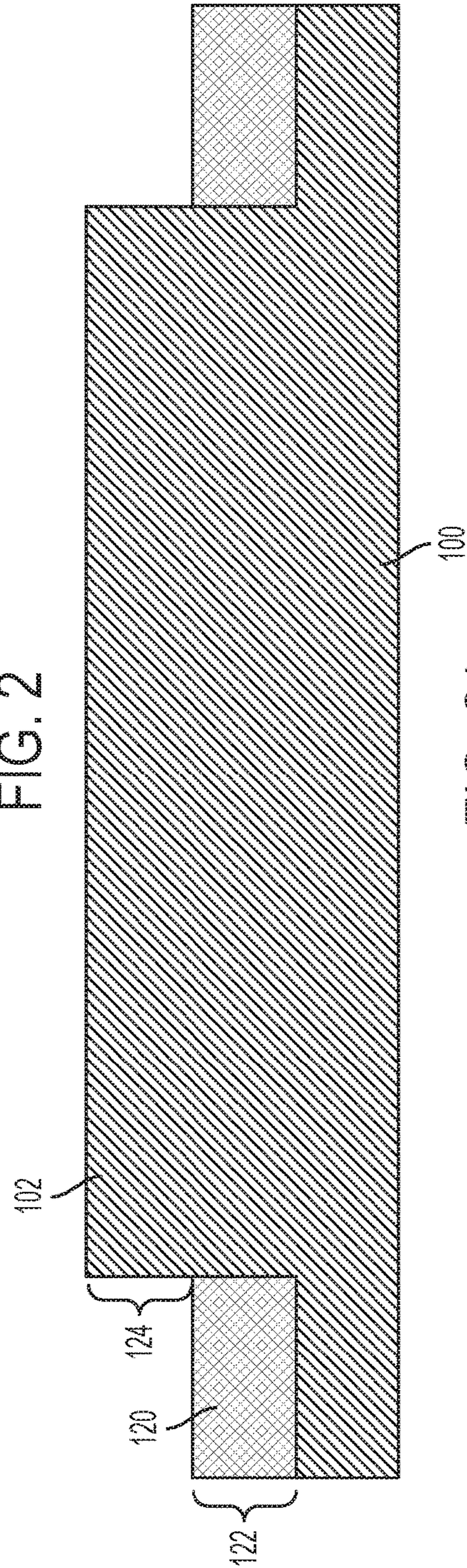


FIG. 2A

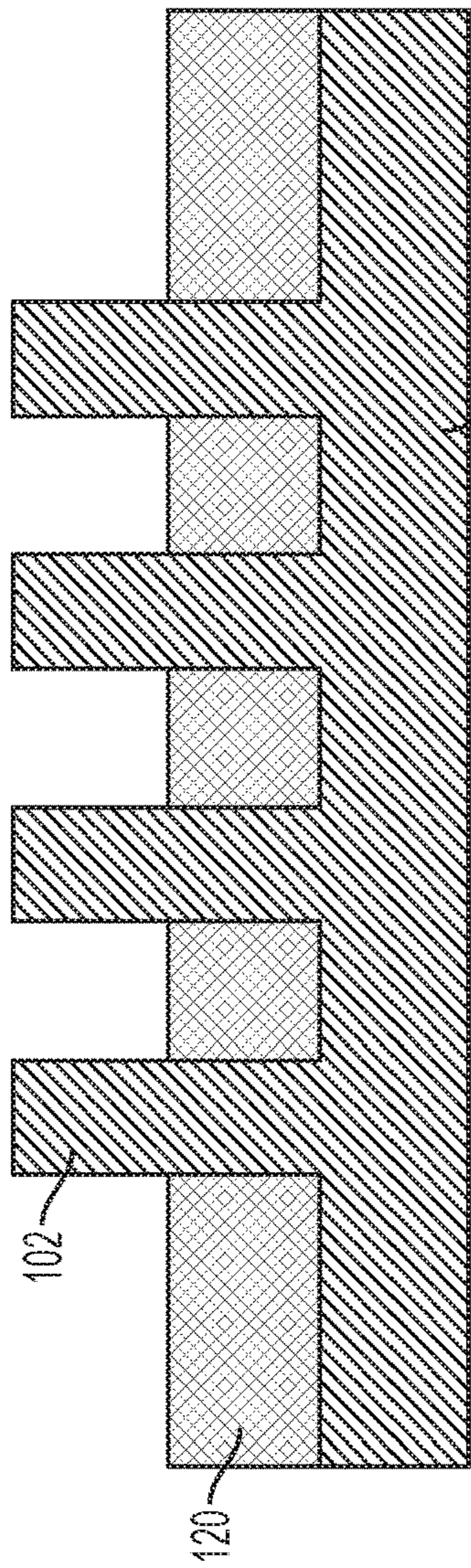


FIG. 2B

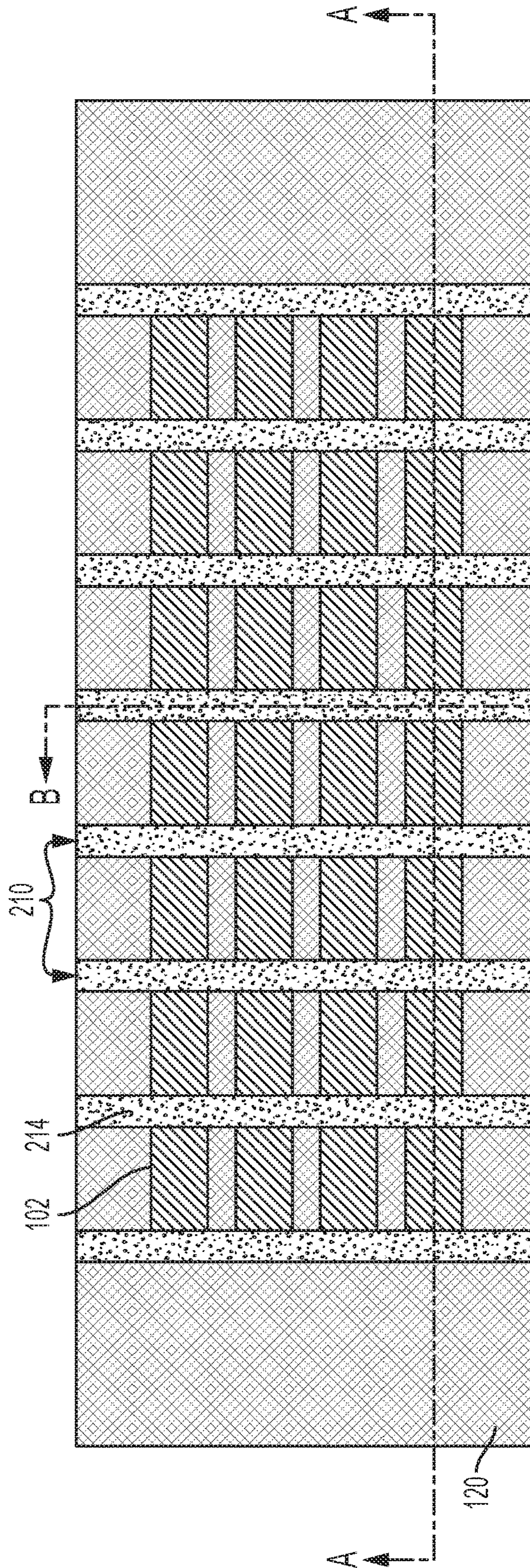
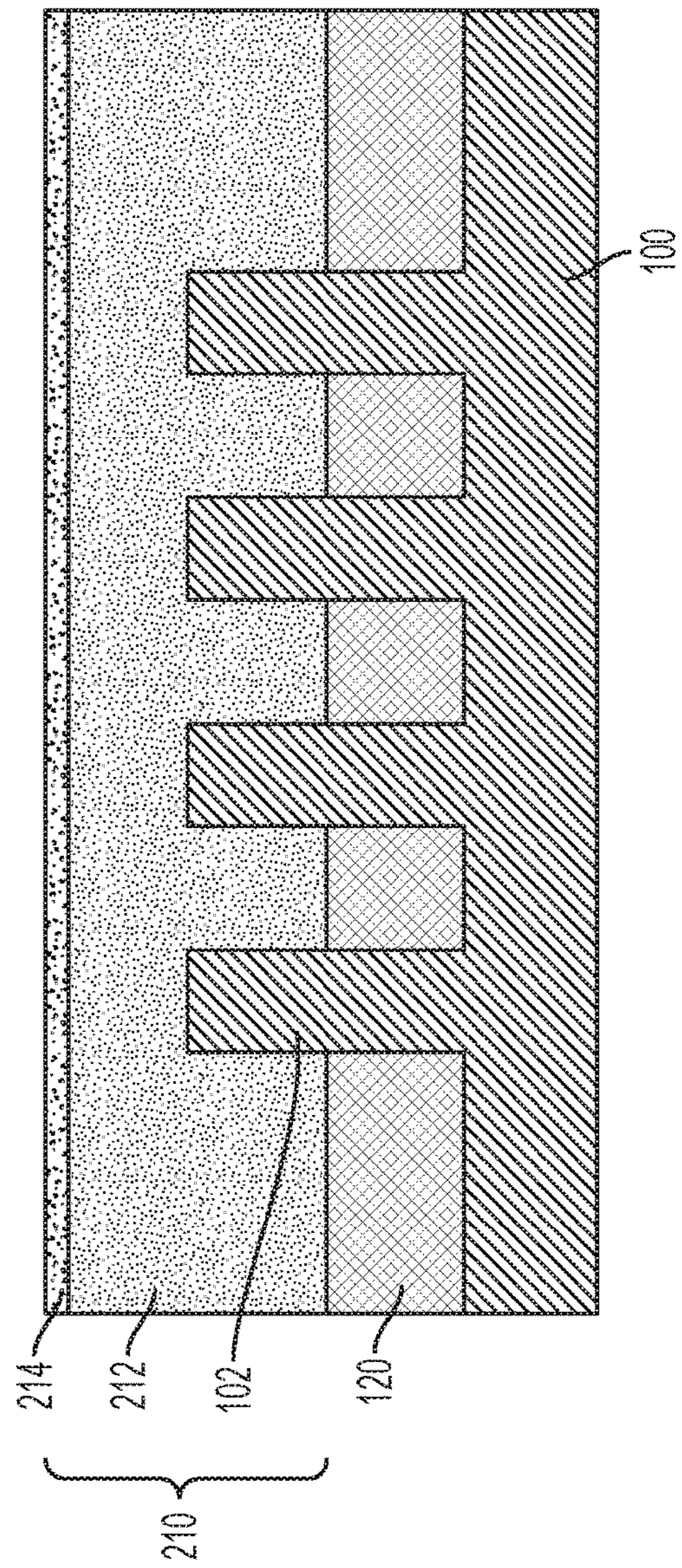
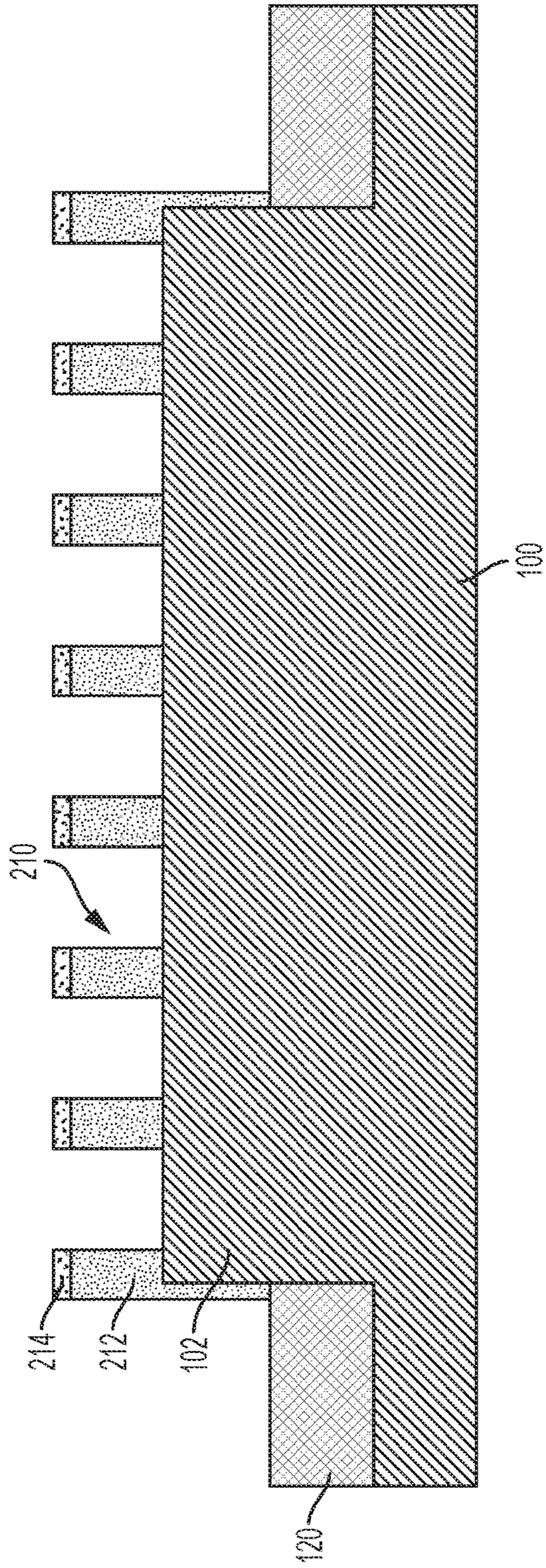


FIG. 3



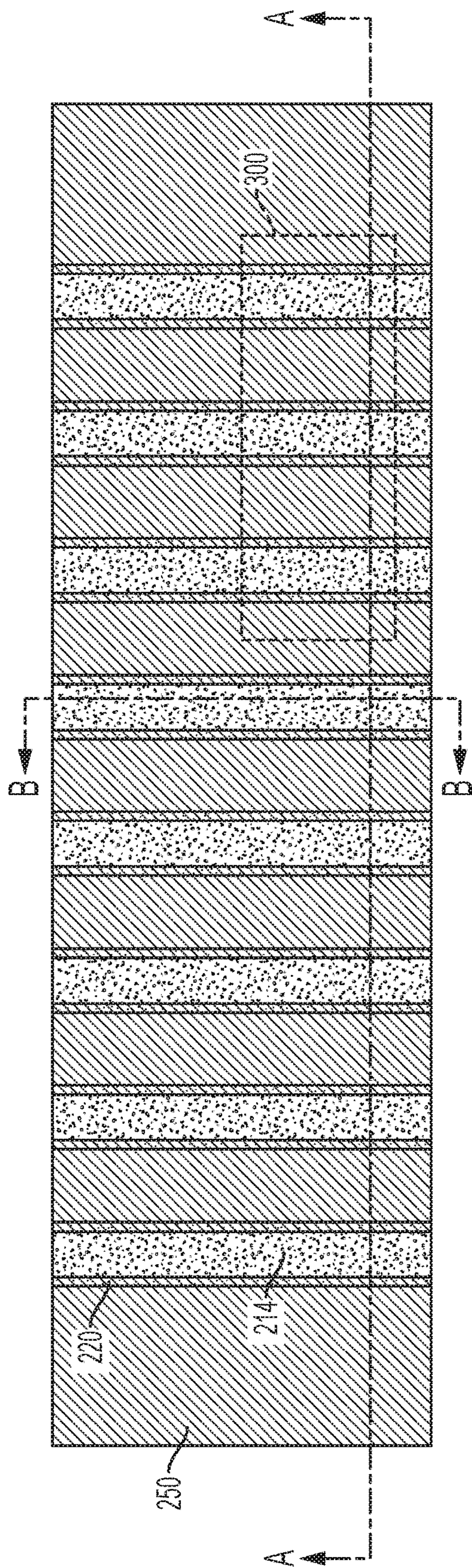


FIG. 4

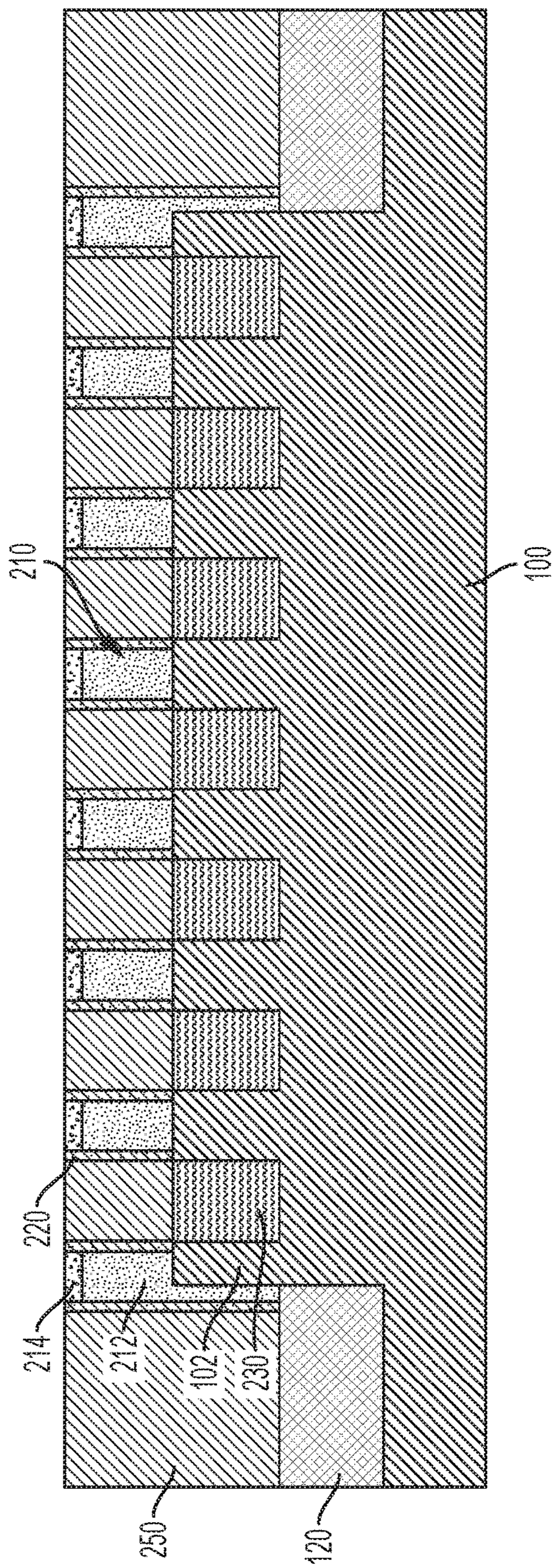


FIG. 4A

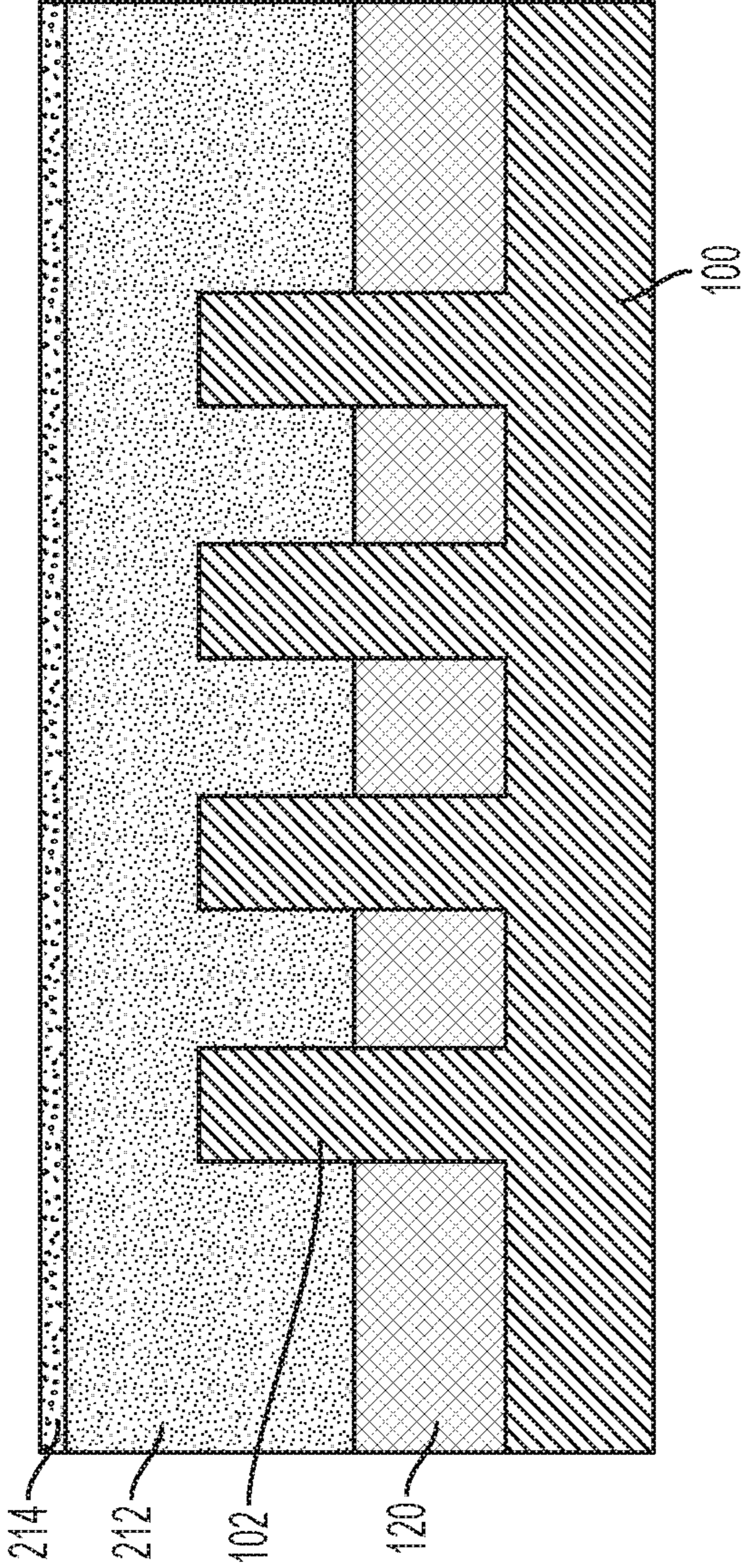


FIG. 4B

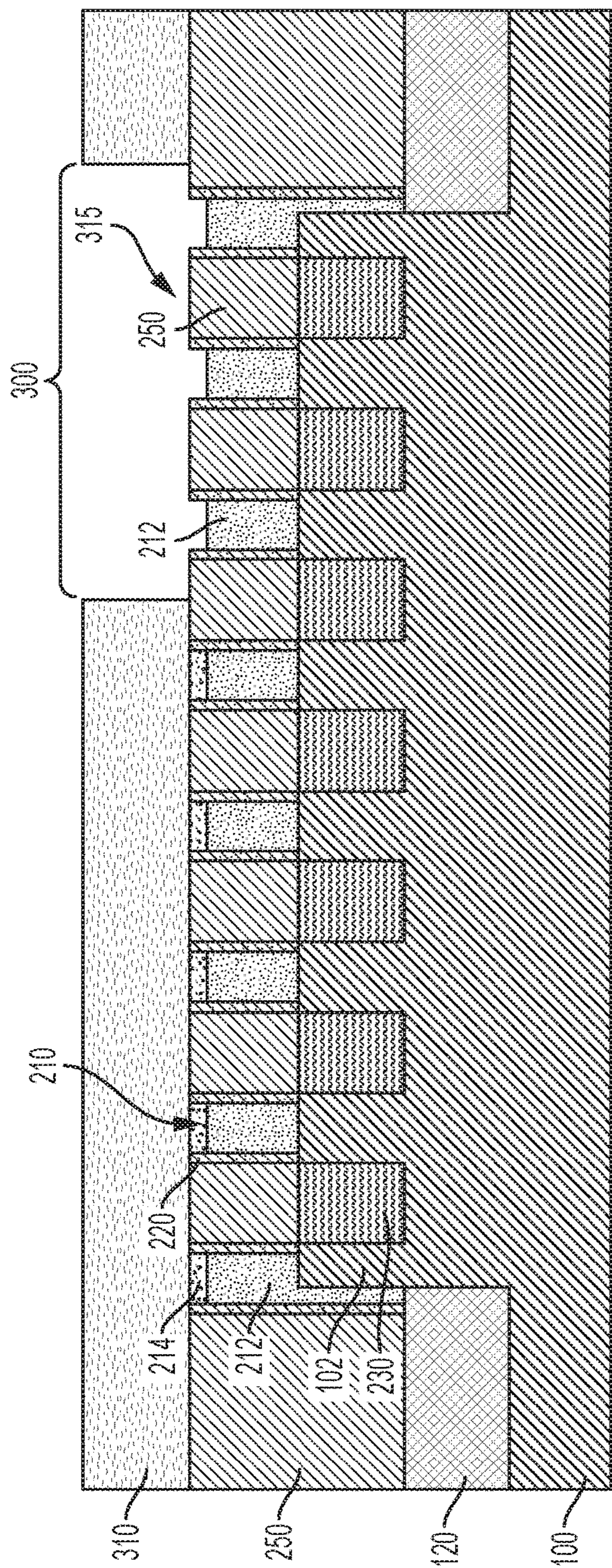


FIG. 5A

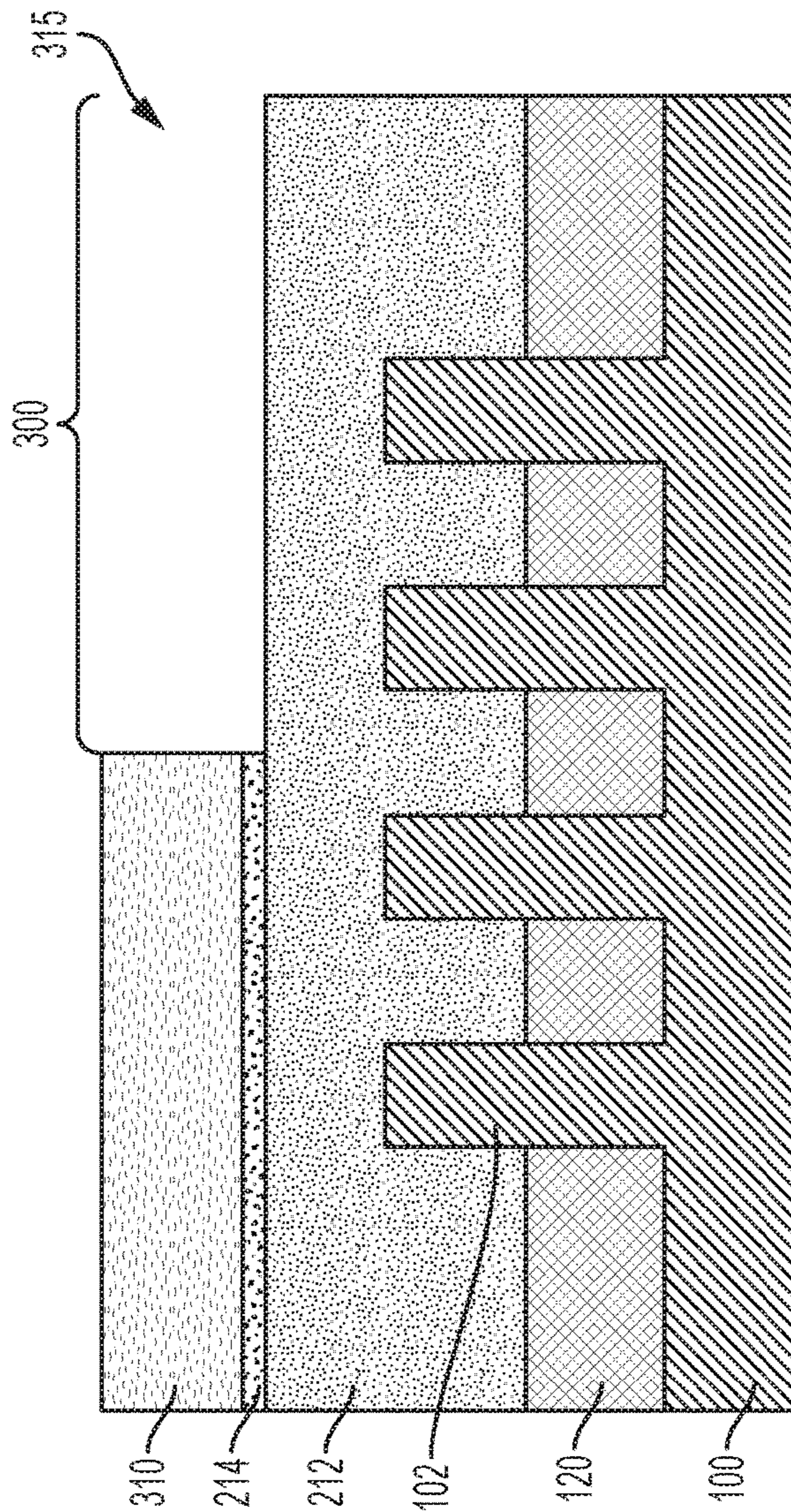


FIG. 5B

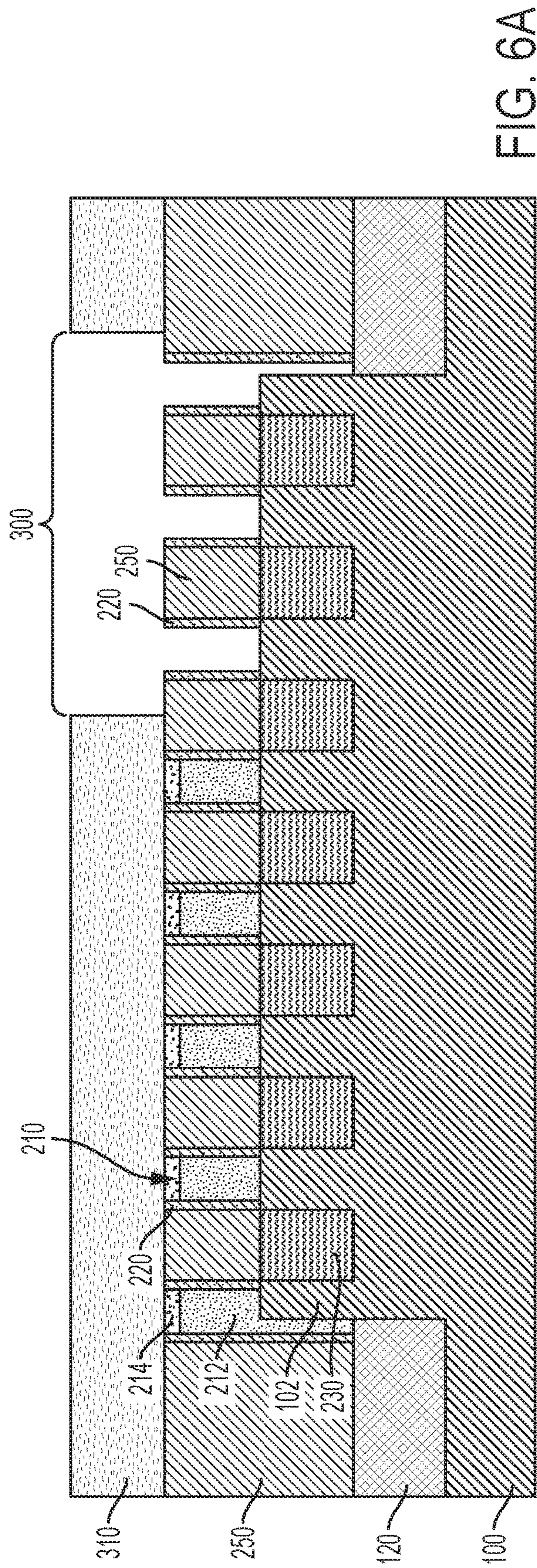


FIG. 6A

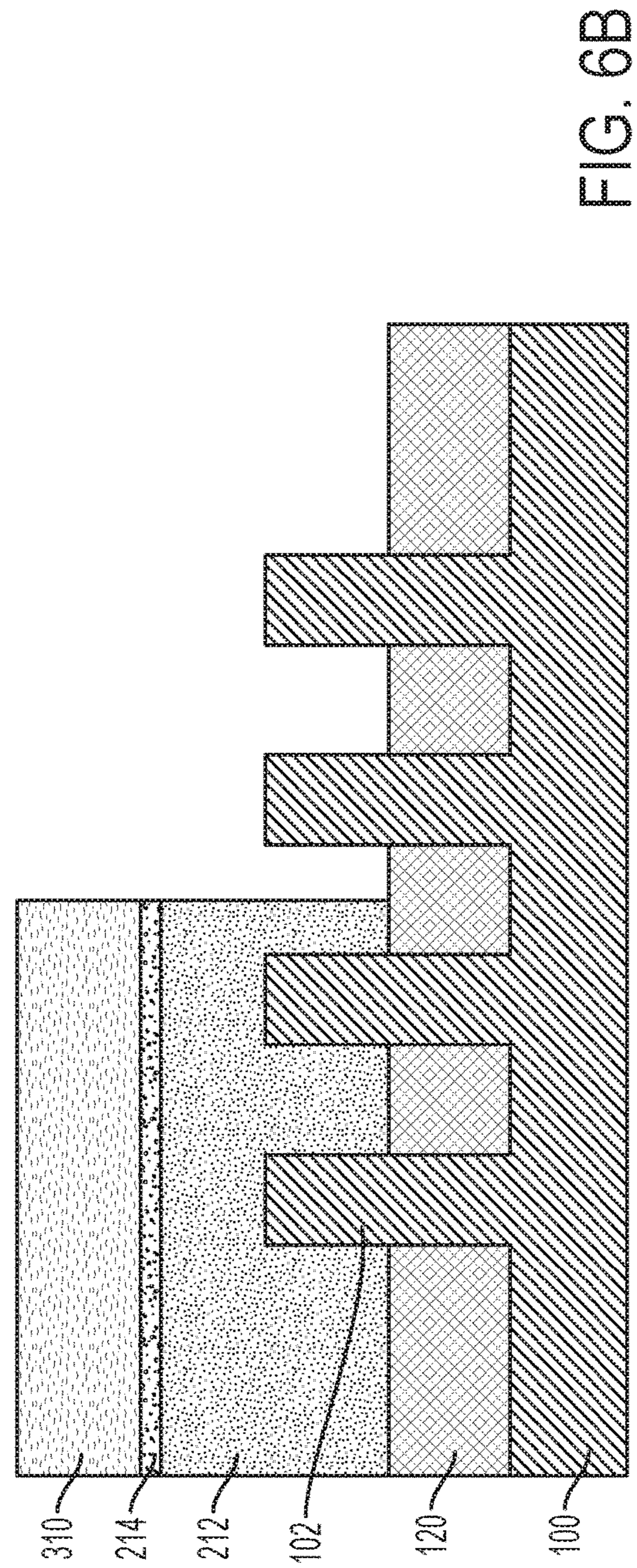


FIG. 6B

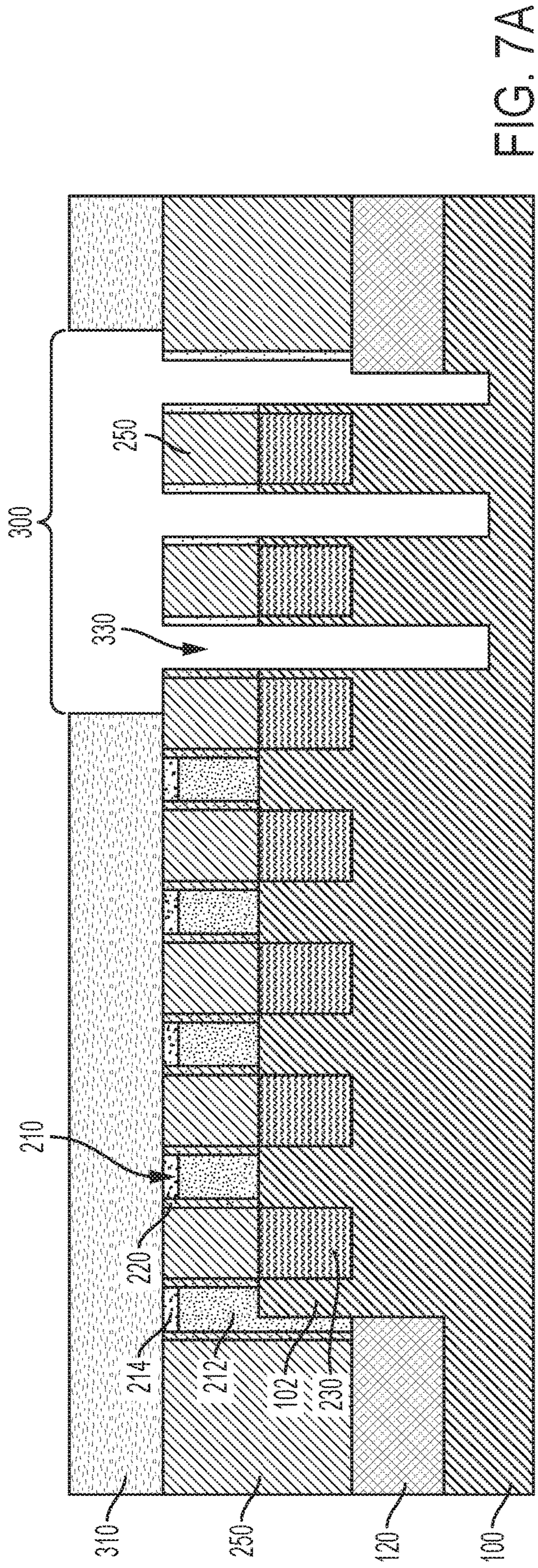


FIG. 7A

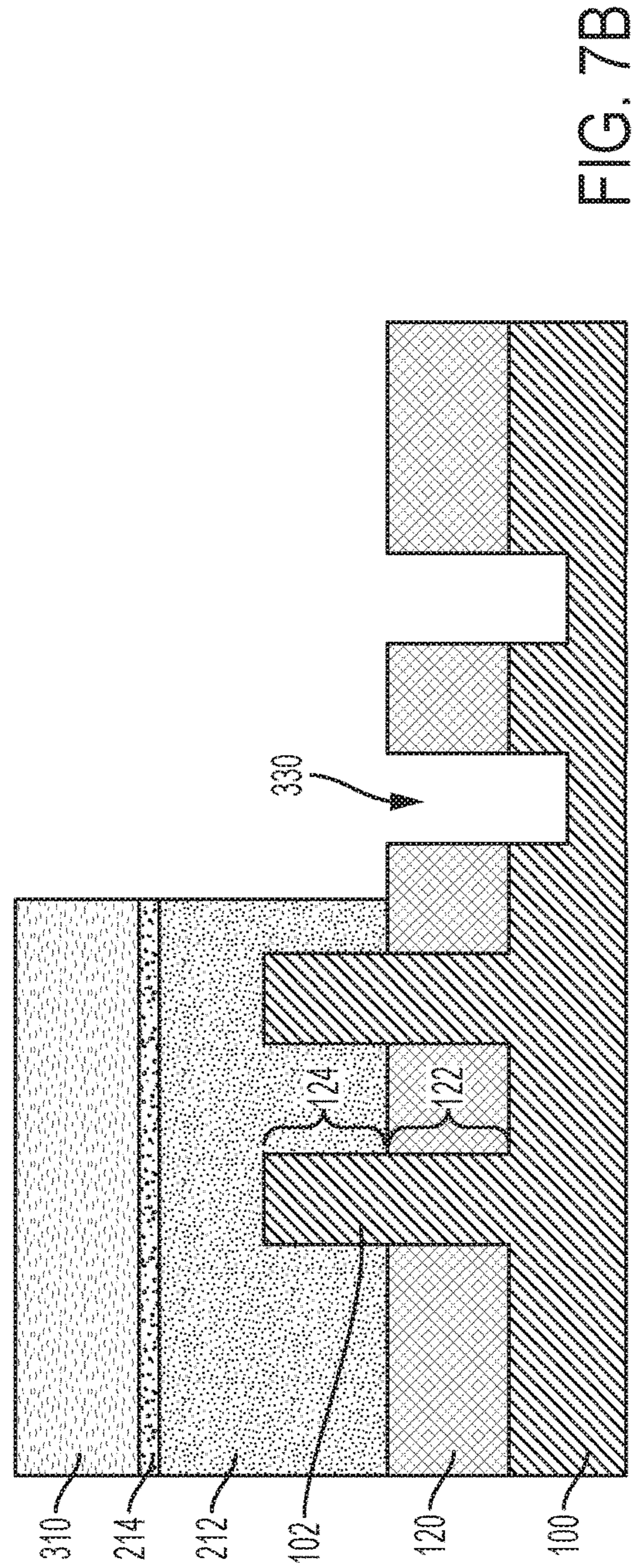


FIG. 7B

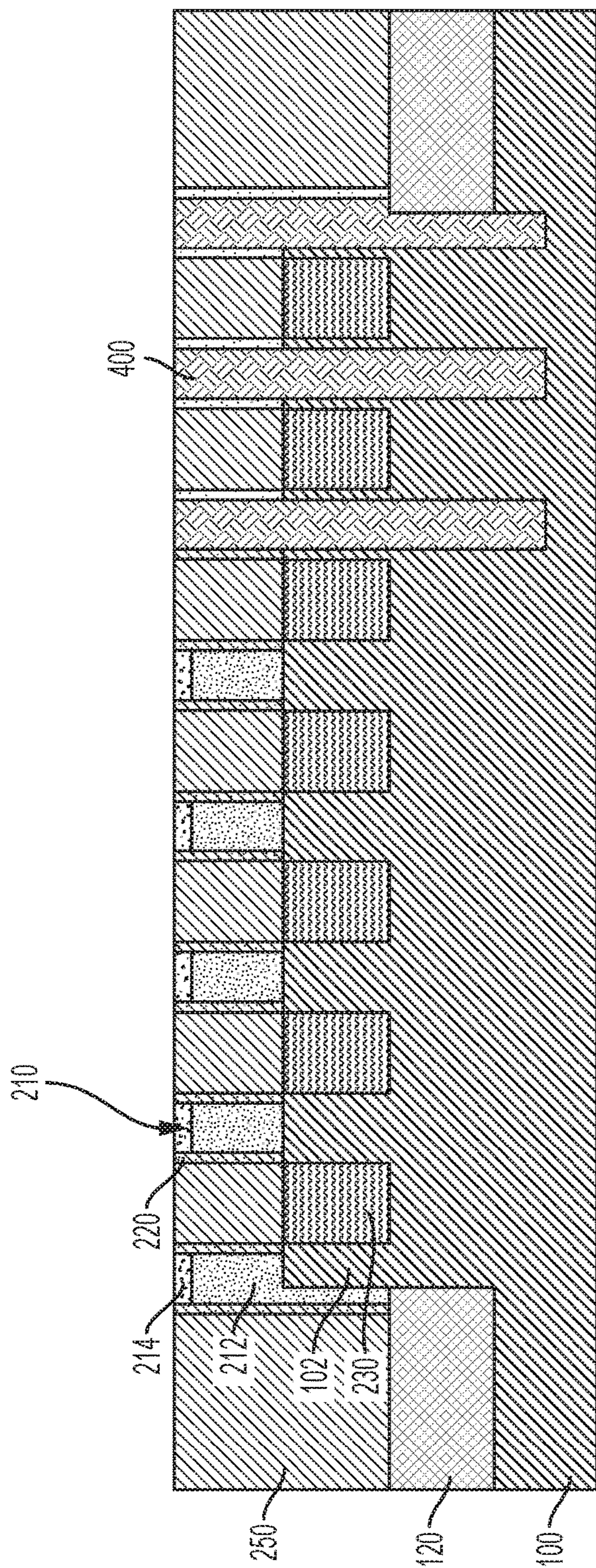


FIG. 8A

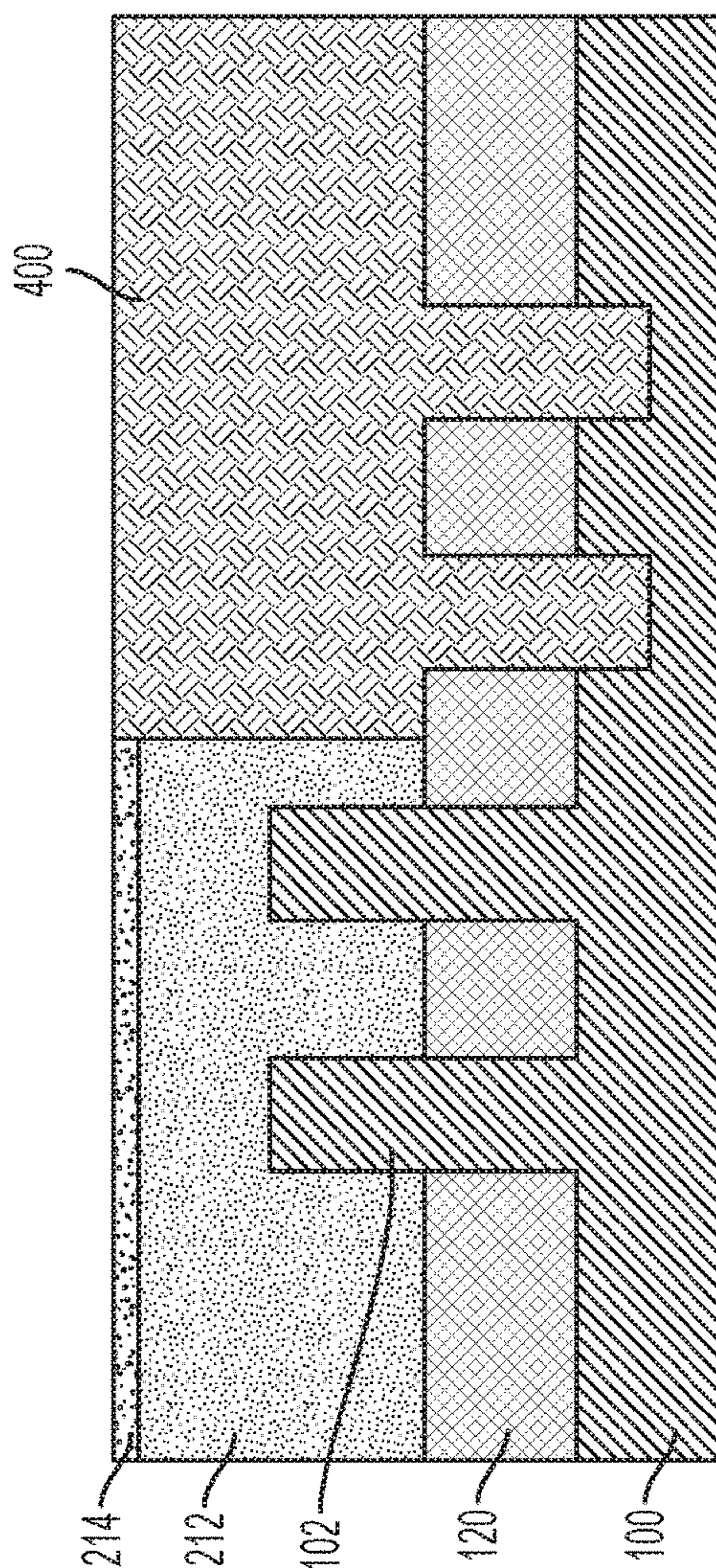


FIG. 8B

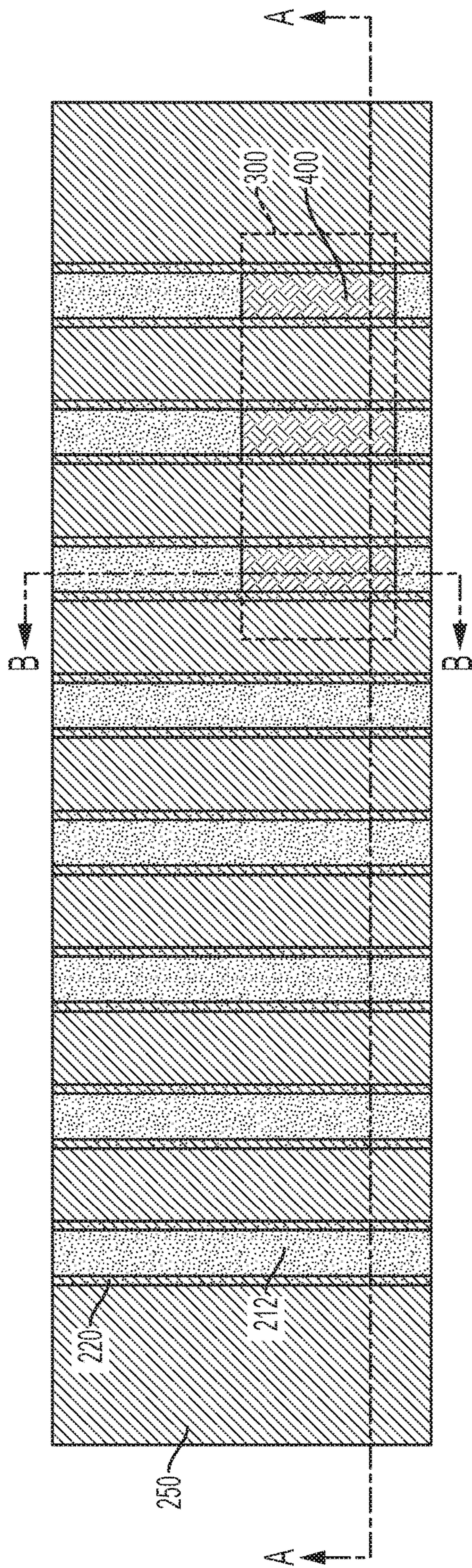


FIG. 9

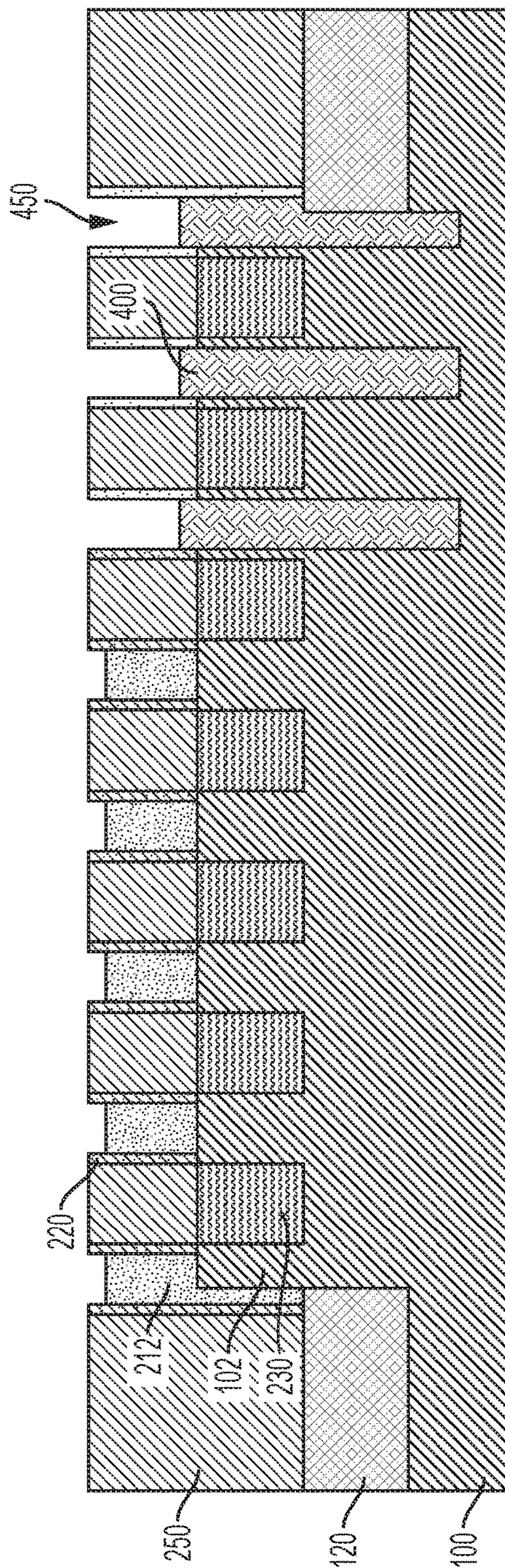


FIG. 9A

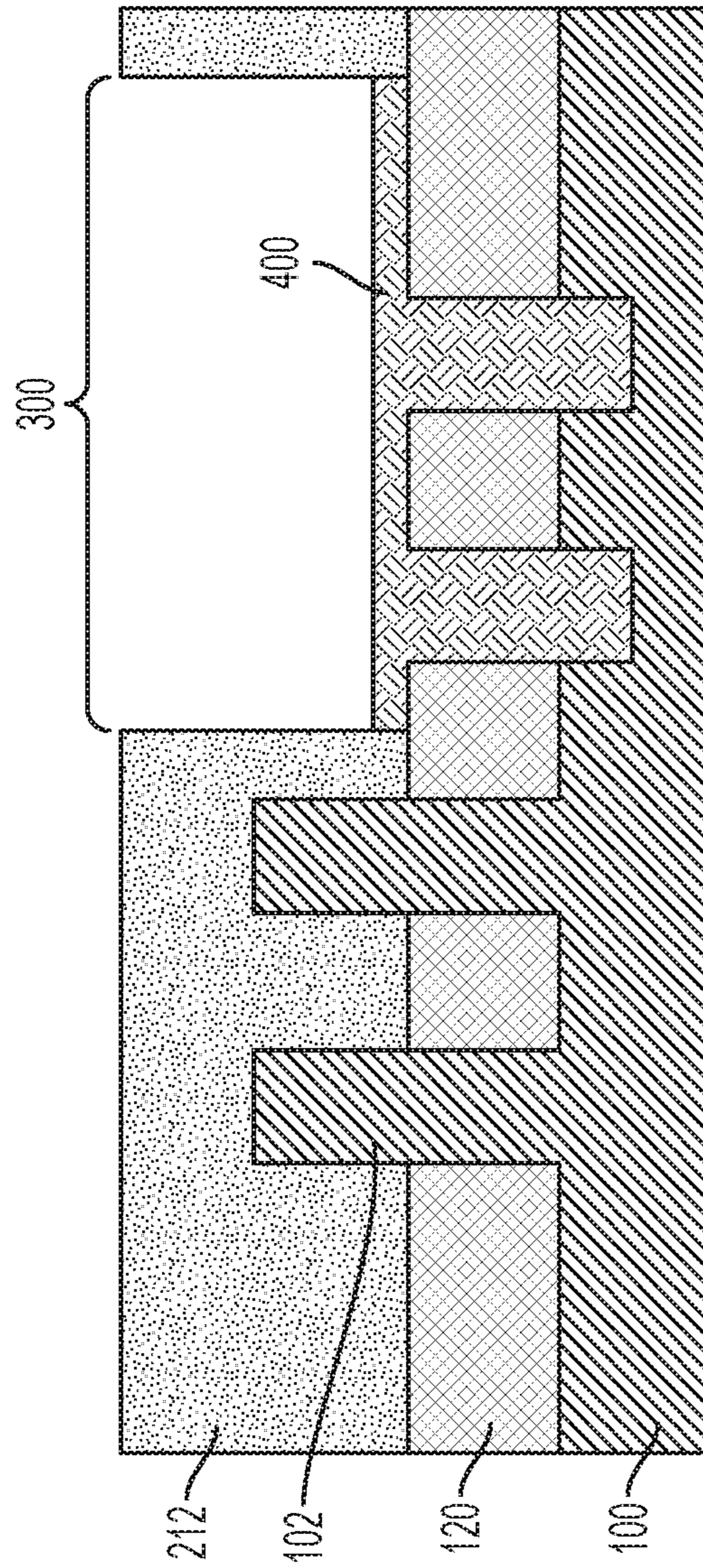


FIG. 9B

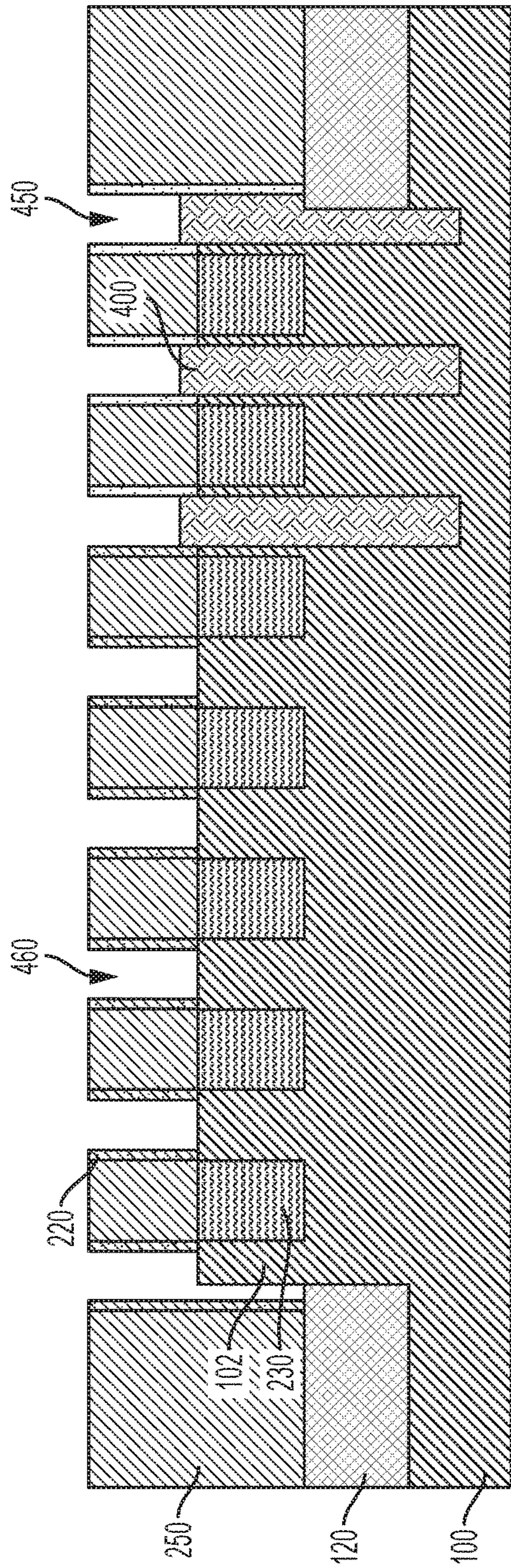


FIG. 10A

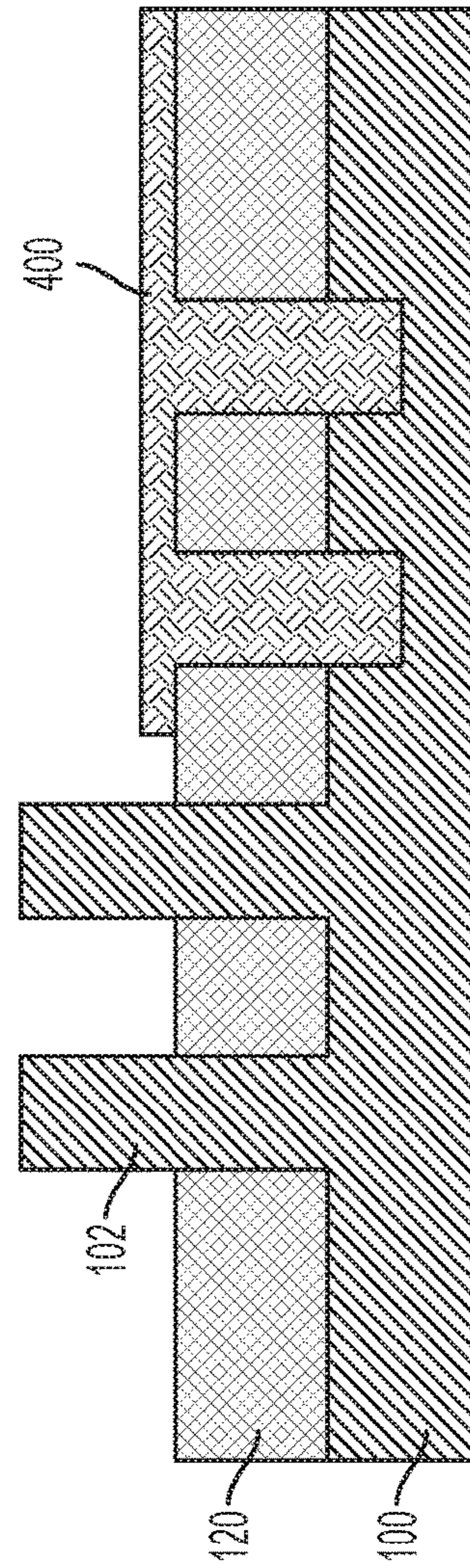


FIG. 10B

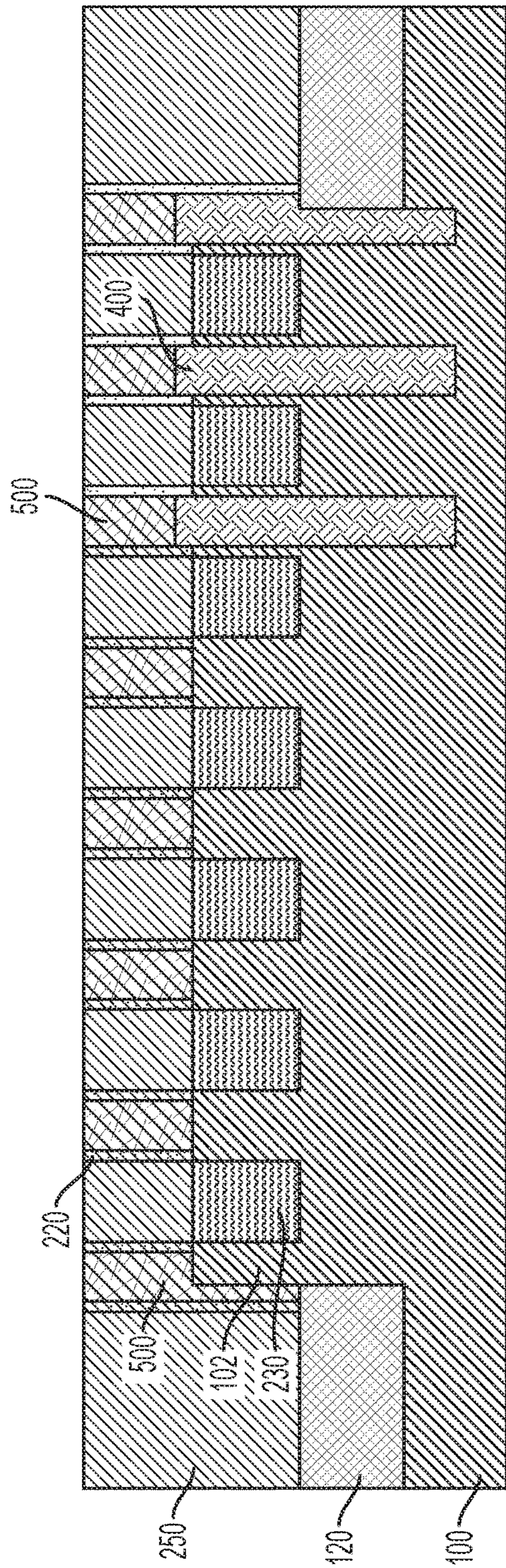


FIG. 11A

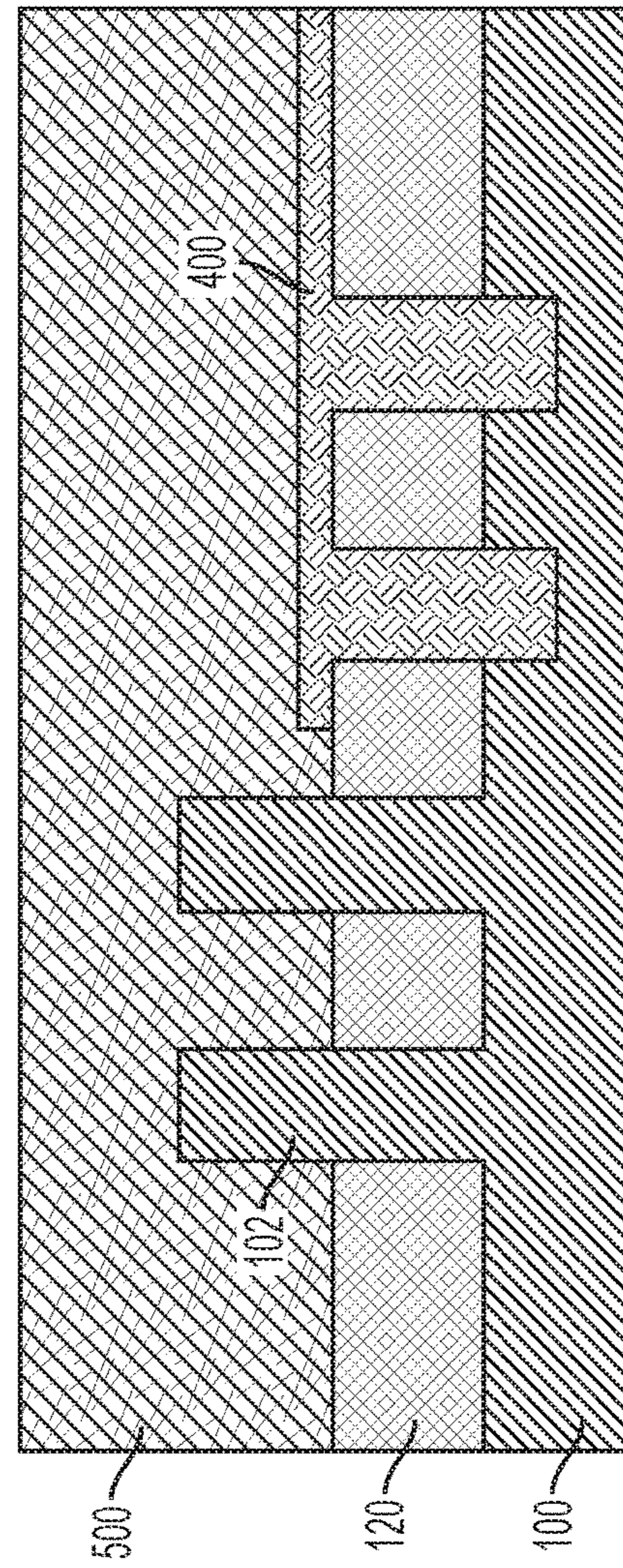
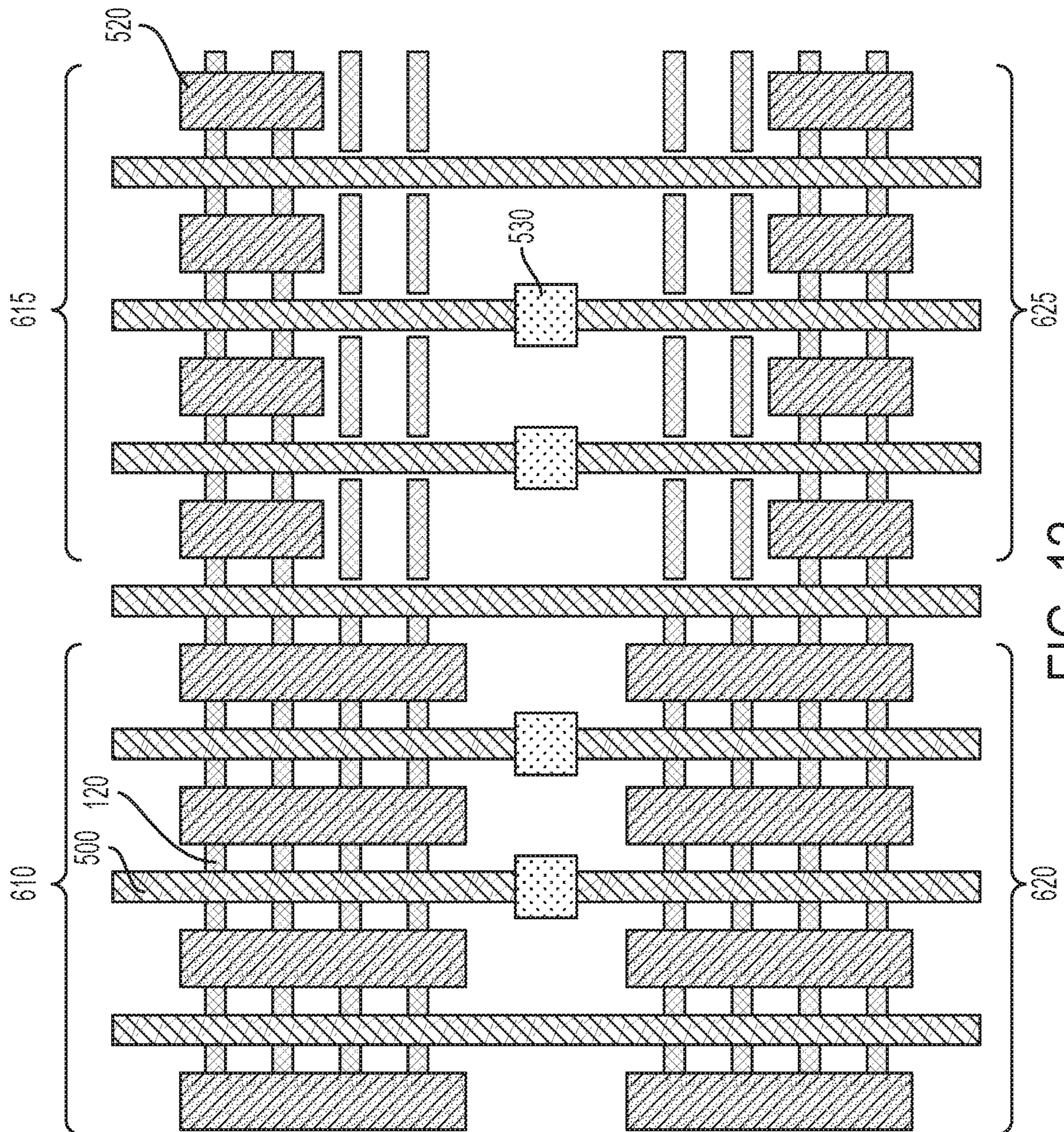


FIG. 11B



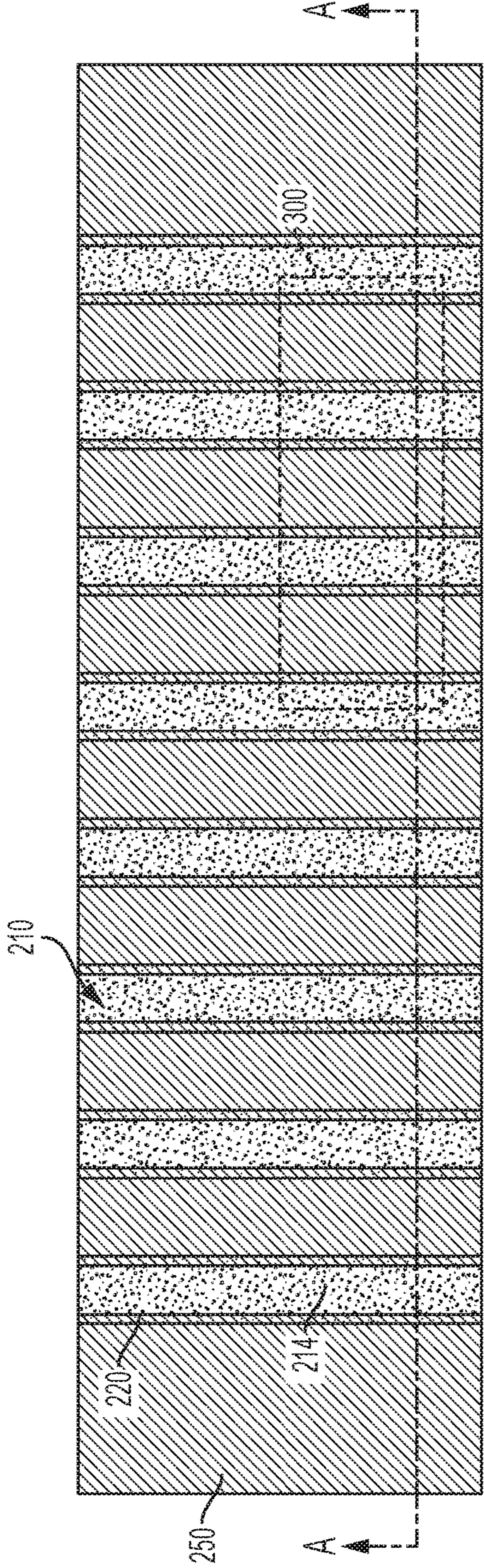


FIG. 13

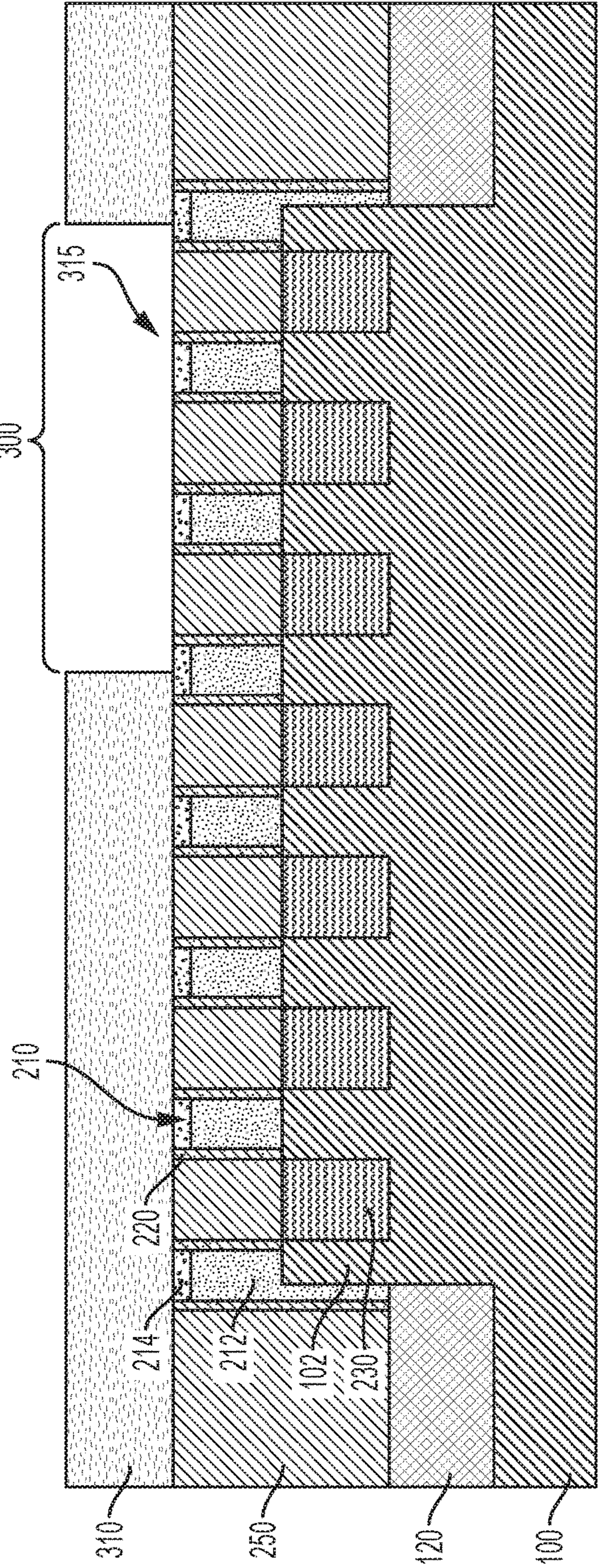


FIG. 14

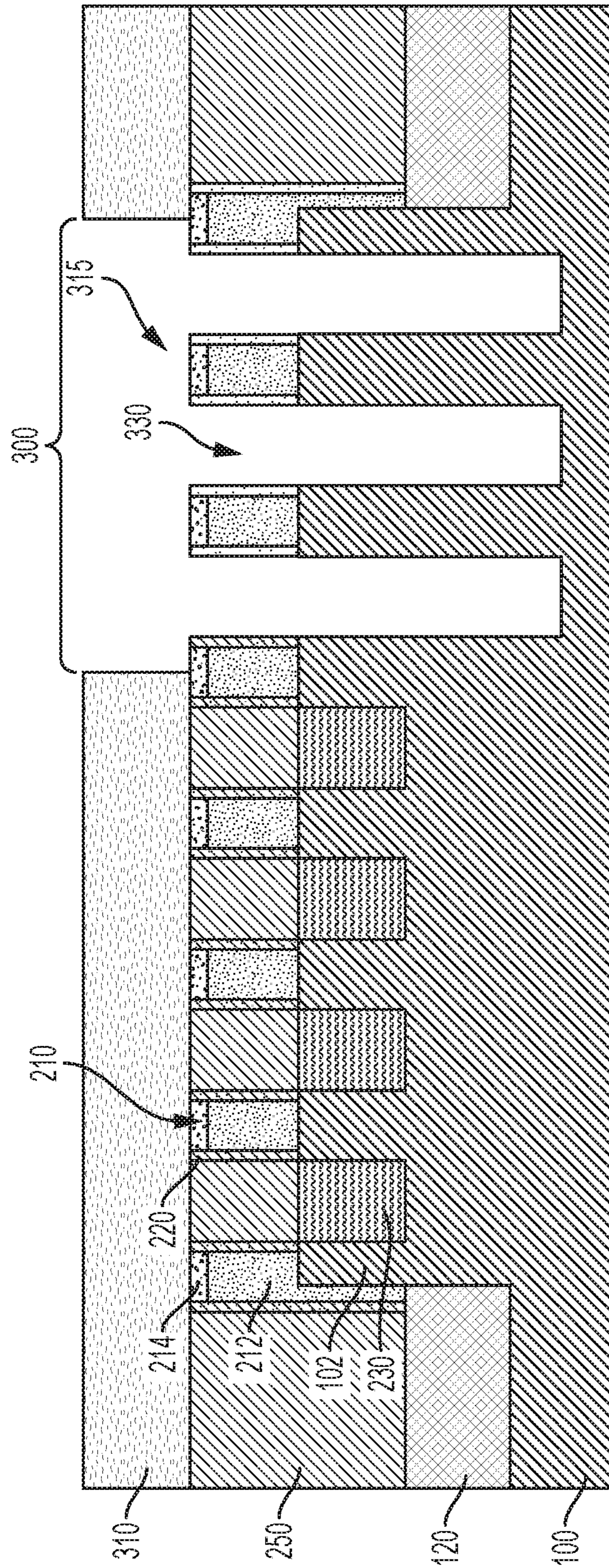


FIG. 15

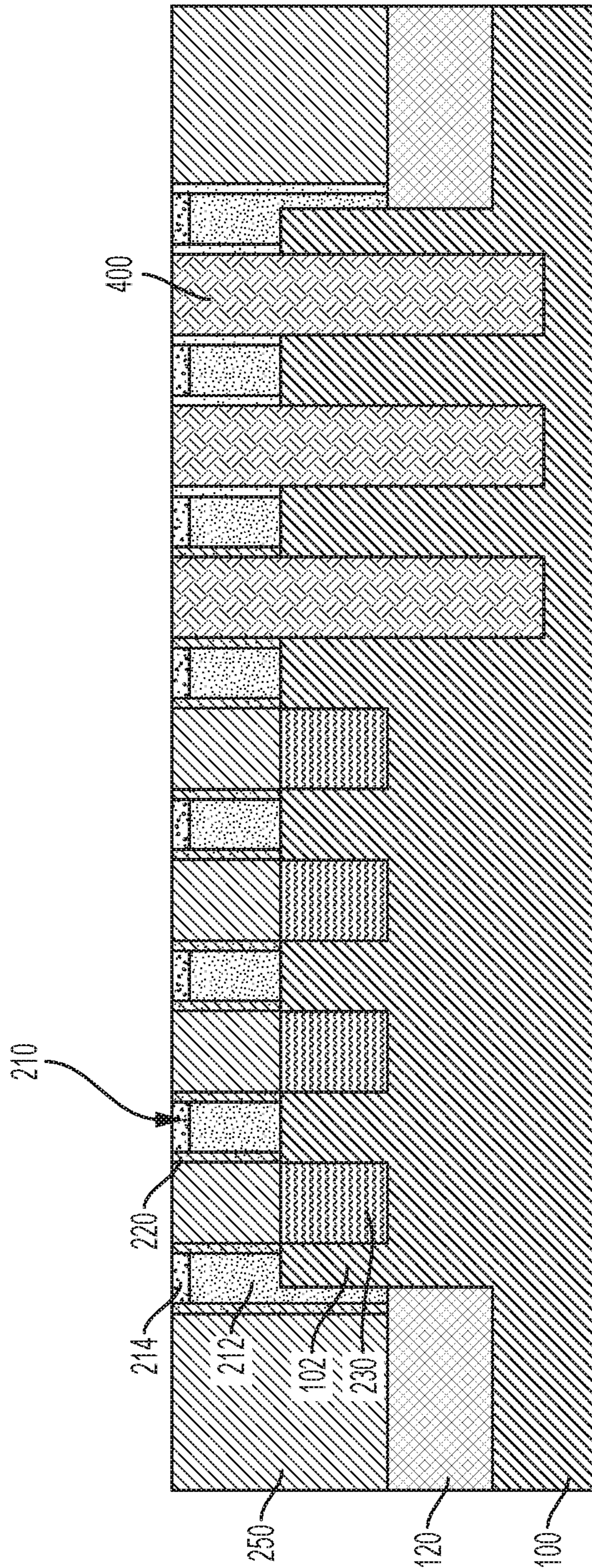


FIG. 16

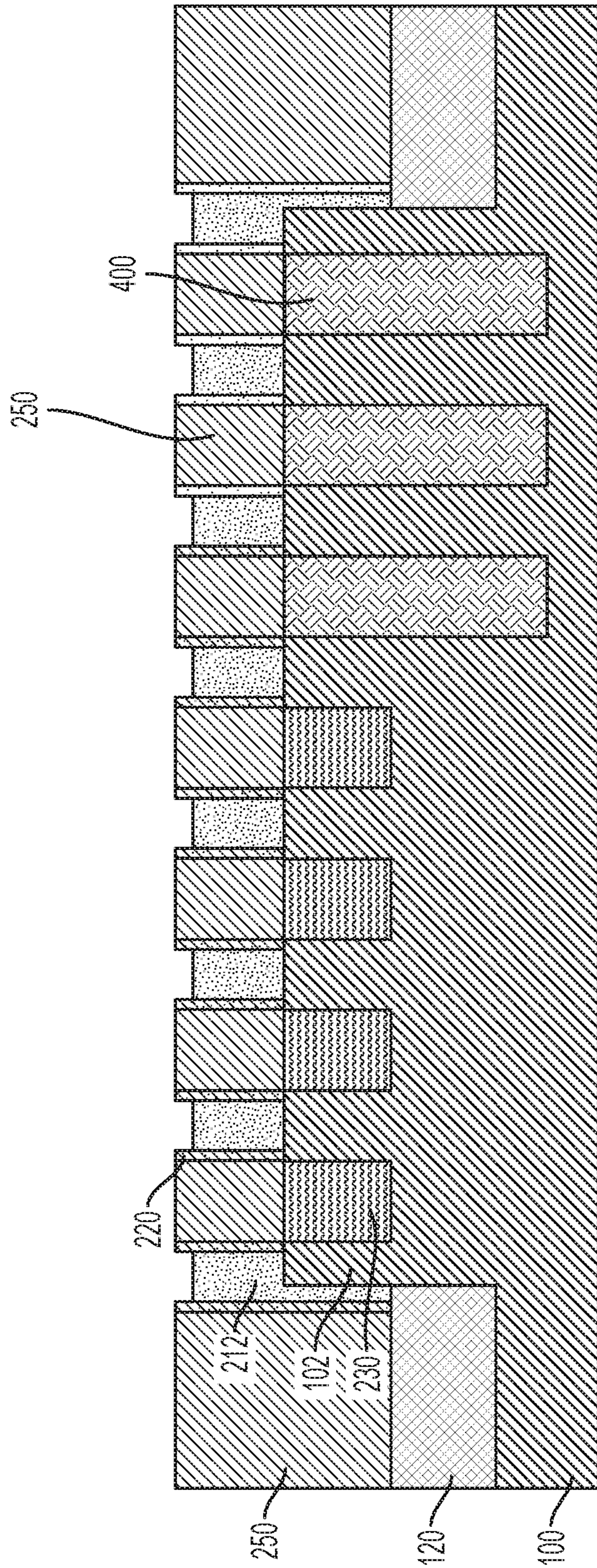


FIG. 17

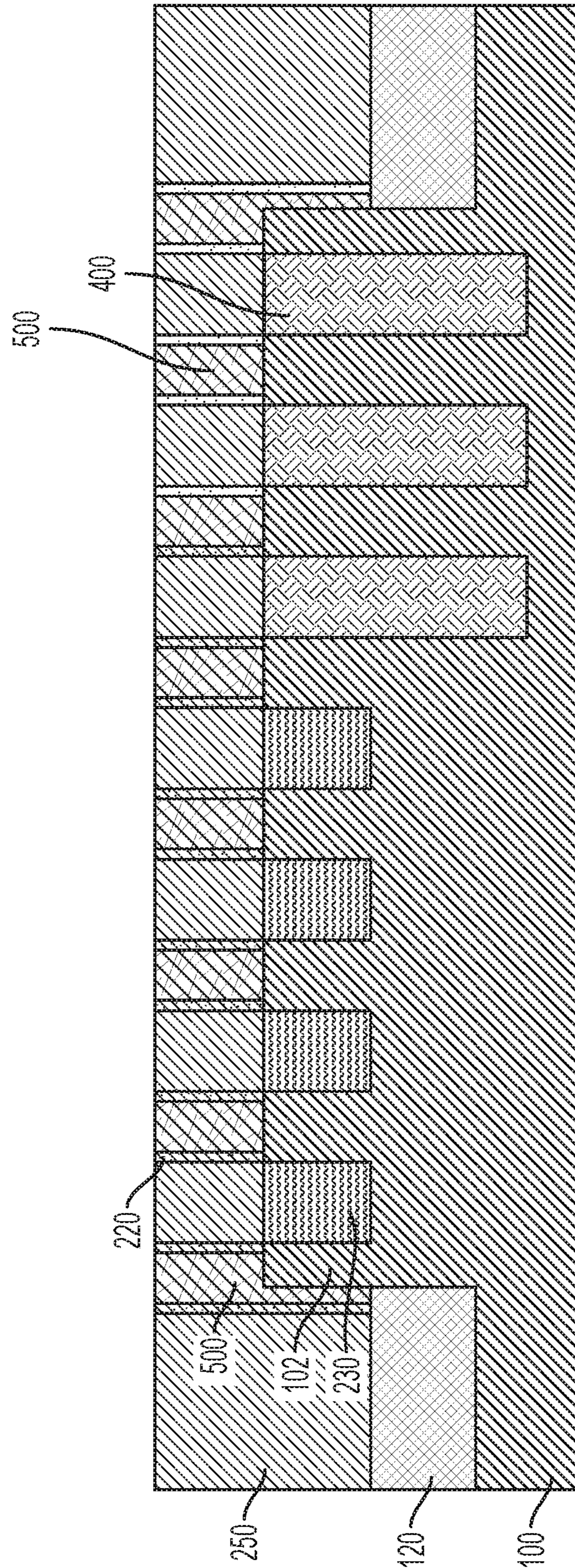


FIG. 18

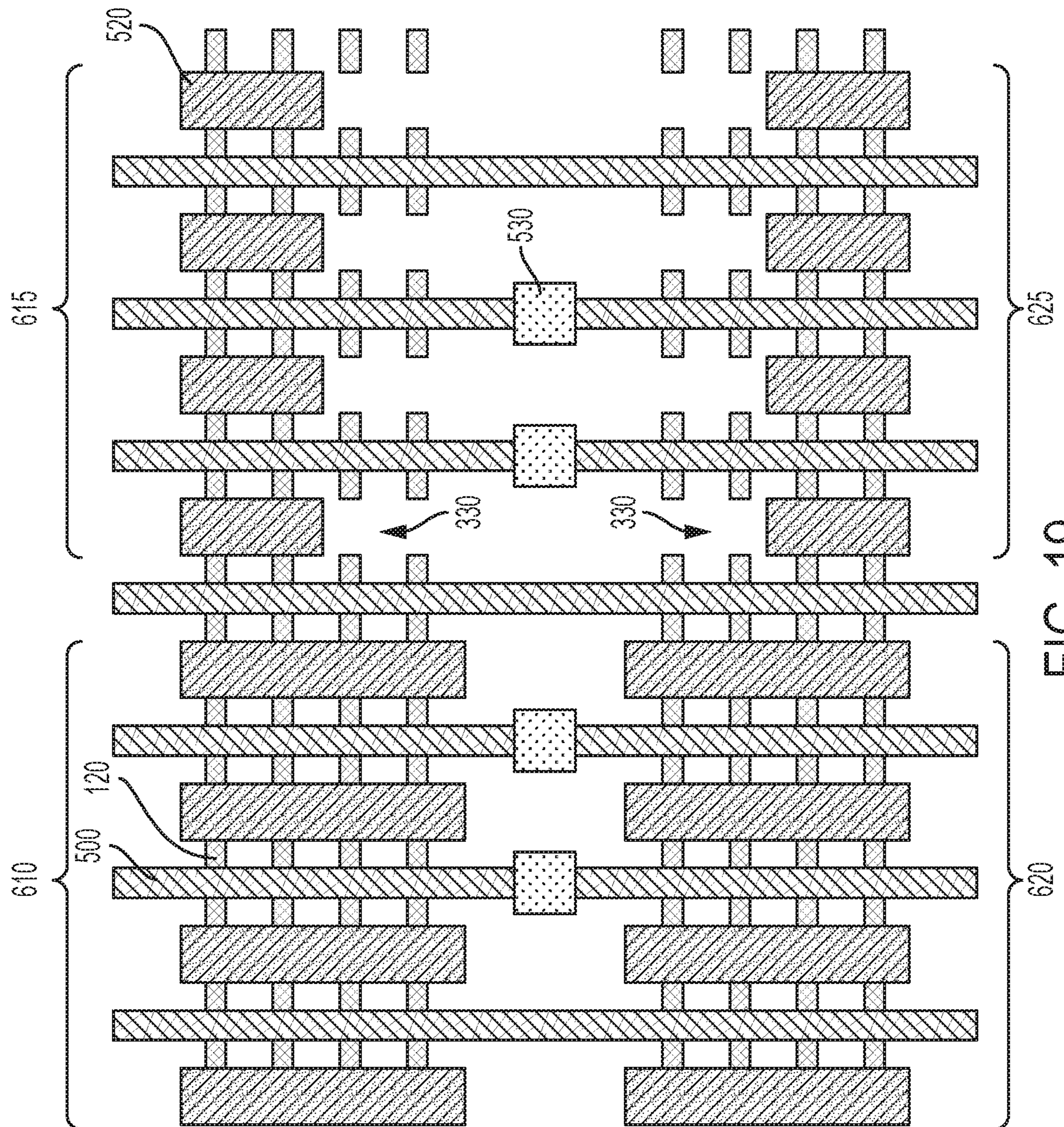


FIG. 19

**METHODS OF PERFORMING FIN CUT
ETCH PROCESSES FOR FINFET
SEMICONDUCTOR DEVICES**

BACKGROUND

The present disclosure generally relates generally to the fabrication of integrated circuits, and more particularly to methods of performing fin cut etch processes for the manufacture of FinFET semiconductor devices.

Fully-depleted devices such as fin field effect transistors (FinFETs) are candidates to enable scaling of next generation gate lengths to 14 nm and below. Fin field effect transistors (FinFETs) present a three-dimensional architecture where the transistor channel is raised above the surface of a semiconductor substrate, rather than locating the channel at or just below the surface. With a raised channel, the gate can be wrapped around the sides of the channel, which provides improved electrostatic control of the device.

The manufacture of FinFETs typically leverages a self-aligned process to produce extremely thin fins, e.g., 20 nm wide or less, on the surface of a substrate using selective-etching techniques. A gate structure is then deposited to contact multiple surfaces of each fin to form a multi-gate architecture over a channel region.

The fins are typically formed in a regular array. As shown in FIG. 1, plural fins **12** may be arranged in parallel, for example, and configured to provide the desired circuit(s) within distinct device regions. To define separate devices, such as a 4-fin device **20** and a 2-fin device **24** on the same substrate, for example, the length of the fins **12** may be adjusted and the fins partitioned by selectively removing some fins or portions of fins. In conventional processing, a fin cut mask (not shown) may be used to define a fin cut region **30**, such that the fin cut mask covers fin portions that are to be retained and exposes other fin portions that are to be removed. After defining the fin cut mask, an etch process forms a fin cut opening **32** that removes the exposed fin portions from within the fin cut region **30**.

As seen schematically in FIG. 1, however, patterning limitations associated with photolithography, in conjunction with strict alignment tolerances that accompany forming devices at advanced nodes, may result in imprecise alignment of the fin cut mask and/or poor fidelity between the fin cut region **30** and the fin cut opening **32**. For example, corner rounding during fin cut patterning may damage or remove fin portions that are intended to be retained. In the hybrid device of FIG. 1, portions of the fins **12** within the 4-fin device region **20** may be undesirably removed.

SUMMARY

Notwithstanding recent developments, processes that cut semiconductor fins with a high-degree of accuracy and precision are desired, particularly for device manufacturing at advanced nodes. In a self-aligned fin cut process for fabricating integrated circuits, as disclosed herein, a sacrificial gate or an epitaxially-formed source/drain region is used in lieu of a lithographically-defined fin cut mask as an etch mask in conjunction with a fin cut etch to remove unwanted portions of the fins.

In accordance with embodiments of the present application, a device includes a plurality of fins disposed over a semiconductor substrate, where the fins include source/drain regions and channel regions extending between the source/drain regions. The device further includes source/drain junctions disposed over the source/drain regions, an interlayer

dielectric disposed over the source/drain junctions, and a functional gate stack disposed over the channel regions, wherein at least one of the plurality of fins has a cut region with a dielectric fill layer disposed within the cut region.

5 In the exemplary device, the dielectric fill layer extends through an entire thickness of the at least one fin, and a pair of opposing edges of the dielectric fill layer are aligned with edges of (i) one of the functional gate stacks, or (ii) one of the source/drain junctions.

10 A method of forming a device includes forming a plurality of fins over a semiconductor substrate, forming a plurality of sacrificial gate stacks over the fins, forming a spacer layer over sidewalls of the sacrificial gate stacks, forming source/drain junctions over exposed portions of the fins between adjacent spacer layers, and forming an interlayer dielectric over the source/drain junctions between adjacent spacer layers.

15 A masking layer is formed over the interlayer dielectric and over the sacrificial gate stacks, and an opening is formed in the masking layer to define a fin cut region. Using the masking layer as an etch mask, the method further includes selectively etching one of (i) the sacrificial gate stacks within the fin cut region, or (ii) the interlayer dielectric and source/drain junctions within the fin cut region to expose the fins within the fin cut region. Fin cut openings are formed by etching the exposed fins, and a dielectric fill layer is formed within the fin cut openings.

20 A further method of forming a device includes forming a plurality of fins over a semiconductor substrate, forming a plurality of sacrificial gate stacks over the fins, forming a spacer layer over sidewalls of the sacrificial gate stacks, forming epitaxial source/drain junctions over exposed portions of the fins between adjacent spacer layers, and forming an interlayer dielectric over the source/drain junctions between adjacent spacer layers.

25 A masking layer is formed over the interlayer dielectric and over the sacrificial gate stacks, and an opening is formed in the masking layer to define a fin cut region. Using the masking layer as an etch mask, the method includes etching one of (i) the sacrificial gate stacks within the fin cut region, or (ii) the interlayer dielectric and the epitaxial source/drain junctions within the fin cut region, to expose the fins within the fin cut region. The exposed fins are etched to form fin cut openings, and a dielectric fill layer is formed within the fin cut openings.

BRIEF DESCRIPTION OF SEVERAL VIEWS OF
THE DRAWINGS

30 The following detailed description of specific embodiments of the present application can be best understood when read in conjunction with the following drawings, where like structure is indicated with like reference numerals and in which:

35 FIG. 1 is a schematic diagram of a FinFET device layout showing a fin cut region and the location of a fin cut opening within a second device region of a semiconductor substrate;

40 FIG. 2 is a top-down schematic plan view diagram showing a plurality of fins arrayed over a semiconductor substrate;

45 FIG. 2A is a cross-sectional view along one of the fins of FIG. 2;

FIG. 2B is a cross-sectional view transverse to the length of the fins;

50 FIG. 3 is a top-down schematic plan view diagram showing the formation of sacrificial gates over the plurality of fins;

FIG. 3A is a cross-sectional view along one of the fins of FIG. 3 showing the overlying sacrificial gates;

FIG. 3B is a cross-sectional view through the plurality of fins showing an overlapping sacrificial gate;

FIG. 4 is a top-down schematic plan view diagram showing a post-planarization architecture including sidewall spacers and an interlayer dielectric formed over the fins, and the location of a fin cut region within a second device region of the substrate;

FIG. 4A is a cross-sectional view showing the formation of the sidewall spacers over the sacrificial gates and the subsequent formation of epitaxial source/drain regions over portions of a fin;

FIG. 4B is a cross-sectional view through the plurality of fins showing an overlying sacrificial gate;

FIG. 5A depicts the formation and patterning of a masking layer defining a fin cut region over a portion of a fin and the removal of the sacrificial gate caps from within the fin cut region;

FIG. 5B shows the location of the masking layer in a cross-sectional view transverse to the view of FIG. 5A;

FIG. 6A depicts selective etching of the sacrificial gates within the fin cut region;

FIG. 6B depicts etching of the sacrificial gates within the fin cut region to expose a plurality of the fins;

FIG. 7A shows anisotropic etching of portions of the fins within the fin cut region using the sidewall spacers and the interlayer dielectric as an etch mask to form fin cut openings;

FIG. 7B shows etching of the fins within the fin cut region;

FIG. 8A shows deposition of a dielectric fill layer within the fin cut openings;

FIG. 8B shows deposition of a dielectric fill layer within the fin cut openings and polishing of the dielectric fill layer;

FIG. 9 is a top-down schematic plan view showing the dielectric fill layer aligned with the sacrificial gates within the fin cut region after removal of the masking layer;

FIG. 9A is a cross-sectional view showing the dielectric fill layer aligned with the sacrificial gates within the fin cut region after removal of the masking layer and a recess etch of the dielectric fill layer;

FIG. 9B is a cross-sectional view showing a recessed dielectric fill layer within the fin cut region;

FIG. 10A shows removal of the remaining sacrificial gates located outside of the fin cut region;

FIG. 10B shows removal of the sacrificial gate from outside of the fin cut region;

FIG. 11A depicts the formation of functional gates over the fins within a first device region and over the recessed dielectric fill layer within the second device region;

FIG. 11B depicts the formation of a functional gate over the fins within the first device region and over the recessed dielectric fill layer within the second device region;

FIG. 12 is a top-down schematic plan view diagram showing a tapered device architecture, including a four fin device located within the first device region and a two fin device located within the second device region;

FIG. 13 is a top-down schematic plan view diagram showing a post-planarization device architecture including sidewall spacers and an interlayer dielectric formed over semiconductor fins, and the location of a fin cut region within a second device region according to further embodiments;

FIG. 14 depicts the formation and patterning of a masking layer defining a fin cut region over a portion of a fin within the second device region;

FIG. 15 shows anisotropic etching of portions of the fins within the fin cut region using the sidewall spacers and the sacrificial gates as an etch mask to form fin cut openings;

FIG. 16 shows deposition of a dielectric fill layer within the fin cut openings and polishing of the dielectric fill layer;

FIG. 17 shows a recess etch of the dielectric fill layer, the deposition of an interlayer dielectric over the recessed dielectric fill layer, and the removal of the sacrificial gate caps to expose the sacrificial gates;

FIG. 18 shows removal of the sacrificial gates and the formation of replacement functional gates over the fins within the first and second device regions; and

FIG. 19 is a top-down schematic plan view diagram showing a tapered device architecture, including a four fin device located within the first device region and an adjacent two fin device located within the second device region.

DETAILED DESCRIPTION

Reference will now be made in greater detail to various embodiments of the subject matter of the present application, some embodiments of which are illustrated in the accompanying drawings. The same reference numerals will be used throughout the drawings to refer to the same or similar parts.

The various components and layers of the structures disclosed herein may be formed using a variety of different materials and methods, e.g., a chemical vapor deposition (CVD) process, an atomic layer deposition (ALD) process, a thermal growth process, spin-coating techniques, etc. The compositions and thicknesses of these various layers of material may vary depending upon the particular application.

Various embodiments related to the formation of hybrid, e.g., tapered, FinFET structures are described herein with reference to FIGS. 2-19. A first embodiment is illustrated in connection with FIGS. 2-12, and a second embodiment is illustrated with reference to FIGS. 13-19. Tapered FinFET structures include a first number of fins within a first device region and a second number of fins within a second, adjacent device region, where the first and second numbers of fins are different and at least one of the fins within the first device region extends into the second device region.

Referring to FIG. 2, a simplified top down plan view schematic diagram of a FinFET architecture at an intermediate stage of fabrication includes a plurality of fins 102 disposed over a semiconductor substrate (not shown). A shallow trench isolation layer 120 is formed over the substrate and between adjacent fins 102. Reference line A is oriented parallel to and along the length dimension of a fin, while reference line B is oriented perpendicular to a length dimension of the fins 102, i.e., across later-formed gates.

Mutually transverse cross-sectional views of the FinFET device structure of FIG. 2 are shown in FIG. 2A and FIG. 2B. FIG. 2A is taken along line A of FIG. 2, and FIG. 2B is taken along line B. The exemplary structure includes a semiconductor substrate 100 and a plurality of semiconductor fins 102 arrayed over the substrate 100.

In the illustrated embodiment, the semiconductor fins 102 are arranged in parallel and are laterally isolated from each other within a sub-fin region 122 by shallow trench isolation layer 120. The fins 102 extend above a top surface of the shallow trench isolation layer (STI) layer 120 and define an active device region 124.

Substrate 100 may include a semiconductor material such as silicon, e.g., single crystal Si or polycrystalline Si, or a silicon-containing material. Silicon-containing materials

include, but are not limited to, single crystal silicon germanium (SiGe), polycrystalline silicon germanium, silicon doped with carbon (Si:C), amorphous Si, as well as combinations and multi-layers thereof. As used herein, the term “single crystal” denotes a crystalline solid, in which the crystal lattice of the entire solid is substantially continuous and substantially unbroken to the edges of the solid with substantially no grain boundaries.

The substrate **100** is not limited to silicon-containing materials, however, as the substrate **100** may include other semiconductor materials, including Ge and compound semiconductors, including III-V compound semiconductors such as GaAs, InAs, GaN, GaP, InSb, ZnSe, and ZnS, and II-VI compound semiconductors such as CdSe, CdS, CdTe, ZnSe, ZnS and ZnTe.

Substrate **100** may be a bulk substrate or a composite substrate such as a semiconductor-on-insulator (SOI) substrate that includes, from bottom to top, a handle portion, an isolation layer (e.g., buried oxide layer), and a semiconductor material layer.

Substrate **100** may have dimensions as typically used in the art and may be, for example, a semiconductor wafer. Example wafer diameters include, but are not limited to, 50, 100, 150, 200, 300 and 450 mm. The total substrate thickness may range from 250 microns to 1500 microns, although in particular embodiments the substrate thickness is in the range of 725 to 775 microns, which corresponds to thickness dimensions commonly used in silicon CMOS processing. The semiconductor substrate **100** may include (100)-oriented silicon or (111)-oriented silicon, for example.

In various embodiments, fins **102** include a semiconductor material such as silicon, and may be formed by patterning and then etching the semiconductor substrate **100**, e.g., a top portion of the semiconductor substrate. In several embodiments, the fins **102** are etched from, and therefore contiguous with the semiconductor substrate **100**. For instance, fins **102** may be formed using a sidewall image transfer (SIT) process as known to those skilled in the art.

In certain embodiments, the fins **102** can have a width of 5 nm to 20 nm and a height of 40 nm to 150 nm, although other dimensions are also contemplated. Fins **102** may be arrayed on the substrate at a regular intrafin spacing or pitch (d). As used herein, the term “pitch” refers to the sum of the fin width and the spacing between a pair of adjacent fins. In example embodiments, the fin pitch (d) within a given device region may be within a range of 20 to 100 nm, e.g., 20, 30, 40, 50, 60, 70, 80, 90 or 100 nm, including ranges between any of the foregoing values, although smaller and larger pitch values may be used.

Shallow trench isolation (STI) layer **120** may be used to provide electrical isolation between the fins **102** and between adjacent devices as is needed for the circuit(s) being formed. An example STI process for FinFET devices involves creating isolation trenches in the semiconductor substrate **100** through an anisotropic etch process. The isolation trench between each adjacent fin may have a relatively high aspect ratio (e.g., ratio of the depth of the isolation trench to its width). A dielectric material, such as silicon dioxide, is deposited into the isolation trenches, for example, using an enhanced high aspect ratio process (eHARP) to fill the isolation trenches. The deposited dielectric material may then be polished by a chemical-mechanical polishing (CMP) process that removes the excess dielectric material and creates a planar STI structure. The planarized oxide is then etched back to form a recessed, uniformly thick oxide isolation layer **120** between the fins **102**, where upper

sidewalls of the fins **102**, i.e., sidewalls within active device region **124**, can be exposed for further processing.

Referring to FIG. 3, FIG. 3A and FIG. 3B, a set of sacrificial gate stacks **210** are arranged orthogonal to and straddle the fins **102**. The sacrificial gate stacks **210** are formed directly over the fins **102** and directly over the STI layer **120**, i.e., over substrate **100**. The sacrificial gate stacks **210** may include a sacrificial gate layer **212** and an overlying sacrificial gate cap **214**, which are deposited in succession and patterned using conventional lithography, for example.

In certain embodiments, the sacrificial gate layer **212** may include a sacrificial oxide layer and an overlayer of amorphous silicon (a-Si), and the sacrificial gate cap **214** may include silicon nitride. Amorphous elemental silicon can be deposited using chemical vapor deposition, such as low pressure chemical vapor deposition (LPCVD) at temperatures ranging from 450° C. to 700° C. Silane (SiH₄) can be used as the precursor for CVD silicon deposition. The sacrificial gate layer **212** may have a thickness sufficient to completely cover the fins. For instance, a thickness of sacrificial gate layer **212** may range from 50 to 200 nm, e.g., 50, 75, 100, 125, 150, 175 or 200 nm, including ranges between any of the foregoing values, although lesser and greater thicknesses may be used.

Referring to FIG. 4, and in particular FIG. 4A and FIG. 4B, sidewall spacers **220** may be formed over sidewalls of the sacrificial gate stack **210** by blanket deposition of a spacer material (e.g., using atomic layer deposition) followed by a directional etch such as reactive ion etching (RIE) to remove the spacer material from horizontal surfaces. Suitable sidewall materials for sidewall spacer **220** include oxides, nitrides and oxynitrides, such as silicon dioxide, silicon nitride, silicon oxynitride, and low dielectric constant (low-k) materials such as amorphous carbon, SiOC, SiOCN and SiBCN, as well as a low-k dielectric material. In certain embodiments, the sidewall spacer **220** thickness is 4 to 20 nm, e.g., 4, 10, 15 or 20 nm, including ranges between any of the foregoing values.

As will be appreciated, the compounds silicon dioxide and silicon nitride have compositions that are nominally represented as SiO₂ and Si₃N₄, respectively. As used herein, the terms silicon dioxide and silicon nitride refer to not only these stoichiometric compositions, but also to oxide and nitride compositions that deviate from the stoichiometric compositions.

Also, as used here, “horizontal” refers to a general direction along a primary surface of a substrate, and “vertical” is a direction generally orthogonal thereto. Furthermore, “vertical” and “horizontal” are generally perpendicular directions relative to one another independent of orientation of the substrate in three-dimensional space.

FIG. 4A shows the structure of FIG. 3A after the deposition of sidewall spacers **220** over the sacrificial gate stacks **210** and the formation of epitaxial source/drain junctions **230** over source/drain regions of the fin **102**.

In the illustrated embodiment, source/drain junctions **230** are disposed over portions of the fins **102** (i.e., source and drain regions) proximate to top surfaces thereof. As known to those skilled in the art, source/drain junctions **230** may be formed by ion implantation or selective epitaxy, optionally using the sacrificial gate stacks **210** and sidewall spacers **220** as an alignment mask. For instance, according to various embodiments, source/drain junctions **230** are formed by selective epitaxy into self-aligned locations that are defined over the fins between the sacrificial gate stacks **210** and over-formed sidewall spacers **220**. That is, source/drain junctions **230** are formed over source and drain regions of

the fins **102** on either side of a channel region, which underlies the sacrificial gate stack **210**.

Source/drain junctions **230** may include silicon (e.g., Si) or a silicon-containing material such as silicon germanium (SiGe). For instance, SiGe source/drain junctions may be incorporated into a p-MOS device to provide compressive stress to the channel, which can improve carrier mobility.

Referring still to FIGS. **4** and **4A**, an interlayer dielectric (ILD) **250** is deposited over the source/drain junctions **230**, i.e., between sacrificial gate stacks **210**. The deposited ILD layer **250**, which may include silicon dioxide or a bi-layer of silicon nitride and an overlying layer of silicon dioxide, may be polished to remove the overburden and create a planarized structure.

“Planarization” refers to a material removal process that employs at least mechanical forces, such as frictional media, to produce a substantially two-dimensional surface. A planarization process may include chemical mechanical polishing (CMP) or grinding. Chemical mechanical polishing (CMP) is a material removal process that uses both chemical reactions and mechanical forces to remove material and planarize a surface.

Referring again to FIG. **4**, a fin cut region **300** identifies, according to several embodiments, the portions of the fins **102** that are to be cut. According to the present embodiment, along the length dimension of the fins, opposing ends of the fin cut region **300** overlie ILD **250**.

Referring to FIG. **5A** and FIG. **5B**, a masking layer **310** (e.g., an organic planarization layer or OPL) is patterned and etched to form an opening **315** aligned with the fin cut region **300**. At the intermediate stage of fabrication shown in the illustrated embodiment, the sacrificial gate cap **214** is removed, and top surfaces of the sacrificial gate layer **212** and the ILD **250** are exposed at the bottom of the opening **315**.

Patterning and etching of masking layer **310** to form the opening **315** may include forming a lithography stack over the masking layer (not shown). For instance, a lithography stack may include one or more of a photoresist layer, an etch stop layer, an amorphous carbon layer, an adhesion layer, an oxide layer, and a nitride layer. Such layers may be configured as known to those skilled in the art to provide a suitable masking layer to pattern and etch the underlying layer(s). According to various embodiments, the areal dimensions of the openings **315** are within lithography process windows for forming such structures.

The pattern transfer etching process to form opening **315** is typically an anisotropic etch. In certain embodiments, a dry etching process such as, for example, reactive ion etching (RIE) can be used. In other embodiments, a wet chemical etchant can be used. In still further embodiments, a combination of dry etching and wet etching can be used.

Referring to FIG. **6A** and FIG. **6B**, after exposing sidewall spacers **220** and ILD **250** within the fin cut region **300**, a selective etch is used to remove the sacrificial gate layer **212** and expose the underlying fin **102**. That is, the selective etch removes the sacrificial gate layer **212** selectively with respect to sidewall spacers **220** and ILD **250**.

As used herein, the terms “selective” or “selectively” in reference to a material removal or etch process denote that the rate of material removal for a first material is greater than the rate of removal for at least another material of the structure to which the material removal process is applied. For example, in certain embodiments, a selective etch may include an etch chemistry that removes a first material selectively to a second material by a ratio of 2:1 or greater, e.g., 5:1, 10:1 or 20:1.

Within the fin cut region **300**, exposed portions of the fins **102** are then etched using a selective fin etch to form fin cut openings **330**. The fin etch may be an isotropic or an anisotropic etch. Silicon, for example, can be etched selectively with respect to the sidewall spacers **220** and ILD **250**. In certain embodiments, as shown in FIG. **7A** and FIG. **7B**, the fin cut etch extends into the substrate **100**, such that portions of both the active device region **124** and the sub-fin region **122** of the fins within the fin cut region **300** are removed.

Referring to FIG. **8A** and FIG. **8B**, fin cut openings **330** created by removing portions of the fins **102** are then back-filled with a dielectric fill layer **400**. Dielectric fill layer **400** may include silicon nitride, for example. The structure can then be planarized, e.g., using the sacrificial gate cap **214** as an etch stop layer. The inlaid dielectric fill layer **400** within the fin cut region **300** is shown in FIG. **9**.

Referring to FIG. **9A** and FIG. **9B**, a recess etch of the dielectric fill layer **400** within the fin cut region **300** defines openings **450**. In the illustrated embodiment, a bottom surface of each opening **450**, i.e., a top surface of the recessed dielectric fill layer **400**, is above a top surface of the fin **102**.

The recess etch of the dielectric fill layer **400** within the fin cut region **300** may precede or accompany a selective etch of the sacrificial gate layer **212** outside of the fin cut region to form openings **460**. The device structure following the recess etch of the dielectric fill layer **400** and removal of the sacrificial gate layer **212** is shown in FIG. **10A** and FIG. **10B**.

Referring to FIG. **11A** and FIG. **11B** a functional gate architecture **500** is formed over the fins **120**, i.e., over the active device region **124** within openings **460** and also within openings **450**. The functional gate architecture **500** includes a gate dielectric layer and one or more gate conductor layers, which are deposited in succession. For simplicity, the individual layers of the gate architecture **500** are not separately shown.

As used herein, a “functional gate” refers to a structure used to control output current (i.e., the flow of carriers through a channel) of a semiconductor device using an electrical field or, in some instances, a magnetic field, and includes a gate dielectric and a gate conductor. Metallization of the functional gates and the source/drain regions may be used to form operable devices.

As will be appreciated, independent transistors may be connected by local interconnection methods and/or back end of the line metallization layers to form integrated circuits, such as SRAM devices. Referring to FIG. **12**, a schematic top-down plan view layout of a FinFET device architecture according to the present embodiment includes a plurality of semiconductor fins **102** arrayed over a semiconductor substrate (not shown). As shown, a first plurality of fins **102** define a first device region **610**. The first plurality of fins within the first device region **610** may define a first four-fin device, such as a PFET device, for example. A second plurality of fins **102** define a second device region **620**. The second plurality of fins within the second device region **620** may define a second four-fin device, such as an NFET device.

Fins **102** extend from first and second device regions **610**, **620** laterally into third and fourth device regions **615**, **625**, respectively. According to the instant embodiment, selected fins **102** within the third and fourth device regions **615**, **625** have been cut by exposing portions of the fins within openings that are formed by removing a sacrificial gate and etching the exposed portions of the fins. With such an

approach, i.e., removing the sacrificial gate and using the sidewall spacers **220** and ILD **250** as an etch mask for a fin cut module, the cut regions of the fins are aligned with the later-formed functional gate **500**. The cut fins enable the formation of a tapered device architecture including, for example, two-fin devices within third and fourth device regions **615**, **625**.

Referring still to FIG. **12**, source/drain contacts **520** overlie source/drain junctions **230** of the fins, and functional gates **500** overlie the fins between adjacent source/drain junctions, i.e., over channel regions of the fins. A gate contact **530** is in electrical contact with gate **500**. In the illustrated embodiment, the first four-fin device and the second four-fin device within the first and second device regions **610**, **620**, respectively, share a common gate **500** and a common gate contact **530**, and the first two-fin device and the second two-fin device within the third and fourth device regions **615**, **625**, respectively, share a common gate **500** and a common gate contact **530**, where the gate and gate contact for the four fin devices is different than the gate and gate contact for the two fin devices. Removal of the sacrificial gate stacks **210** as well as the recess etch of the dielectric fill layer **400** allows each replacement gate **500** to traverse multiple fins. That is, within the third and fourth device regions **615**, **625**, gate **500** overlies uncut fins and is aligned with the fin cut(s).

Further, fins **102** that form the first two-fin device within the third device region **615** are common to a subset of the fins that form the first four-fin device within the first device region **610**, and fins that form the second two-fin device within the fourth device region **625** are common to a subset of the fins that form the second four-fin device within the second device region **620**.

The instant method of severing selected fins to form two fin devices, e.g., where a lower drive current may be required compared to four fin device, produces a fin cut that is aligned to the later-formed gate, and obviates etch damage to the fins, e.g., within source/drain regions thereof.

According to a further embodiment, the sacrificial gate stack and the sidewall spacers can be used as an etch mask for a fin cut module by first removing the ILD **250** and source/drain junction **230** overlying the fin. Referring to FIG. **13**, following the formation of a plurality of fins, sacrificial gate stacks **210** over the fins, sidewall spacers **220** over the sacrificial gate stacks **210**, source/drain junctions and a planarized ILD layer **250**, a top down plan view schematic diagram of a FinFET architecture includes a fin cut region **300** defined according to a further embodiment. In the illustrated structure, along the length dimension of the fins **120**, opposing ends of the fin cut region **300** shown in FIG. **13** overlie sacrificial gate stacks **210**.

Thus, as in the previous embodiment, the fin cut region **300** defines the portions of fins that are to be cut. In lieu of removing the sacrificial gate stacks within the gate cut opening and using the sidewall spacers and ILD layer as an etch mask to cut the fins, however, according to the present embodiment, the ILD layer and source/drain junctions are removed within the fin cut region **300**, and the sacrificial gate stack **210** and sidewall spacers **220** are used as an etch mask to cut the fins.

Referring to FIG. **14**, masking layer **310** (e.g., an organic planarization layer or OPL) is patterned and etched to form an opening **315** in the masking layer **310** aligned with the fin cut region **300**. The structure following a selective etch within the fin cut region **300** of the ILD layer **250**, source/drain junctions **230** and exposed fins **102** is shown in FIG. **15**. As in the previous embodiment, the fin cut etch extends

into the substrate **100**, such that both the active device region **124** and the sub-fin region **122** of the fins within the fin cut region **300** are removed to form fin cut openings **330**.

Referring to FIG. **16**, openings **330** created by removing the fins **102** are then back-filled with a dielectric fill layer **400**. The structure can be planarized to remove the dielectric fill layer overburden, e.g., using the sacrificial gate cap **214** as an etch stop layer.

Referring to FIG. **17**, shown is the structure of FIG. **16** following a recess etch of the dielectric fill layer **400**, deposition of an interlayer dielectric **250** within the recesses, and removal of the sacrificial gate cap **214** from over the sacrificial gate layer **212**. In certain embodiments, the dielectric fill layer **400** includes silicon nitride and the interlayer dielectric **250** includes silicon dioxide. In such case, replacing a nitride layer with an oxide layer may beneficially decrease the capacitance of the circuit. Referring to FIG. **18**, the sacrificial gate layer **212** is removed and replaced with a functional gate architecture **500**. In the present embodiment, the functional gate architecture **500** is formed over fins inside and outside of the fin cut region.

Referring to FIG. **19**, shown is a schematic top-down plan view layout of a FinFET device architecture according to the present embodiment. The tapered device architecture includes a plurality of semiconductor fins **102** arrayed over a semiconductor substrate (not shown).

In the illustrated embodiment, each of first and second device regions **610**, **620** includes a four-fin device, such as a PFET device and an NFET device, respectively. Fins **120** from the first and second device regions extend laterally into third and fourth device regions **615**, **625**, where selected fins have been cut and the remaining fins form two-fin devices. The fin cut openings **330** within the third and fourth device regions are aligned to the source/drain contacts **520**, which overlie source/drain junctions.

As will be readily apparent to those skilled in the art, the methods and structures disclosed herein may be employed in manufacturing a variety of different devices, including, but not limited to, logic devices, memory devices, etc., and the devices may be either PMOS or NMOS devices.

As used herein, the singular forms “a,” “an” and “the” include plural referents unless the context clearly dictates otherwise. Thus, for example, reference to a “fin” includes examples having two or more such “fins” unless the context clearly indicates otherwise.

Unless otherwise expressly stated, it is in no way intended that any method set forth herein be construed as requiring that its steps be performed in a specific order. Accordingly, where a method claim does not actually recite an order to be followed by its steps or it is not otherwise specifically stated in the claims or descriptions that the steps are to be limited to a specific order, it is no way intended that any particular order be inferred. Any recited single or multiple feature or aspect in any one claim can be combined or permuted with any other recited feature or aspect in any other claim or claims.

It will be understood that when an element such as a layer, region or substrate is referred to as being formed on, deposited on, or disposed “on” or “over” another element, it can be directly on the other element or intervening elements may also be present. In contrast, when an element is referred to as being “directly on” or “directly over” another element, no intervening elements are present.

While various features, elements or steps of particular embodiments may be disclosed using the transitional phrase “comprising,” it is to be understood that alternative embodiments, including those that may be described using the

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transitional phrases “consisting” or “consisting essentially of,” are implied. Thus, for example, implied alternative embodiments to a sacrificial gate that comprises amorphous silicon include embodiments where a sacrificial gate consists essentially of amorphous silicon and embodiments where a sacrificial gate consists of amorphous silicon.

It will be apparent to those skilled in the art that various modifications and variations can be made to the present invention without departing from the spirit and scope of the invention. Since modifications, combinations, sub-combinations and variations of the disclosed embodiments incorporating the spirit and substance of the invention may occur to persons skilled in the art, the invention should be construed to include everything within the scope of the appended claims and their equivalents.

What is claimed is:

1. A device comprising:

a plurality of fins disposed over a semiconductor substrate, the fins comprising source/drain regions and channel regions extending between the source/drain regions;

source/drain junctions disposed over the source/drain regions;

an interlayer dielectric disposed over the source/drain junctions;

a cut opening located between an adjacent pair of the source/drain junctions and extending into the semiconductor substrate;

a dielectric fill layer disposed within a bottom portion of the cut opening, wherein a top surface of the dielectric fill layer extends to or above a top surface of the fins and extends to a top surface of the source/drain junctions;

and

a functional gate stack disposed over each of the channel regions of the plurality of fins and within a top portion of the cut opening over and contacting the top surface of the dielectric fill layer, wherein a pair of opposing edges of the dielectric fill layer within the cut opening are aligned with edges of (i) the functional gate stack within the top portion of the cut opening, or (ii) one of the adjacent pair of the source/drain junctions.

2. The device of claim 1, wherein the functional gate stack within the top portion of the cut opening directly overlies the dielectric fill layer within the bottom portion of the cut opening.

3. The device of claim 1, wherein the dielectric fill layer comprises silicon nitride.

4. The device of claim 1, wherein the pair of opposing edges are oriented perpendicular to a length direction of at least one of the plurality of fins.

5. The device of claim 1, further comprising a spacer layer disposed over sidewalls of the interlayer dielectric.

6. The device of claim 5, wherein the spacer layer comprises silicon nitride.

7. The device of claim 1, wherein the dielectric fill layer extends into the semiconductor substrate a distance greater than a length of each of the plurality of fins.

8. The device of claim 1, wherein the plurality of fins include a first plurality of fins within a first region of the semiconductor substrate and a second plurality of fins with a second region of the semiconductor substrate, wherein the cut opening is disposed within the second region of the semiconductor substrate.

9. The device of claim 1, wherein the plurality of fins include a first plurality of fins within a first region of the semiconductor substrate and a second plurality of fins with

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a second region of the substrate, and at least one of the second plurality of fins extends into the first region.

10. A device comprising:

a plurality of fins disposed over a semiconductor substrate, the plurality of fins including source/drain regions and channel regions extending between the source/drain regions;

source/drain junctions disposed over the source/drain regions of the plurality of fins;

an interlayer dielectric disposed over the source/drain junctions;

a cut opening located between an adjacent pair of the source/drain junctions and extending into the semiconductor substrate;

a dielectric fill layer disposed within a bottom portion of the cut opening, wherein a top surface of the dielectric fill layer extends to or above a top surface of the fins and extends to a top surface of the source/drain junctions;

and

a functional gate stack disposed over each of the channel regions of the plurality of fins and within a top portion of the cut opening over and contacting the top surface of the dielectric fill layer, wherein a pair of opposing edges of the dielectric fill layer within the top portion of the cut opening are aligned with edges of the functional gate stack within the top portion of the cut opening.

11. The device of claim 10, wherein the functional gate stack within the top portion of the cut opening directly overlies the dielectric fill layer within the bottom portion of the cut opening.

12. The device of claim 10, wherein the pair of opposing edges are oriented perpendicular to a length direction of at least one of the plurality of fins.

13. The device of claim 10, further comprising a silicon nitride spacer layer disposed over sidewalls of the interlayer dielectric.

14. The device of claim 10, wherein the dielectric fill layer extends into the semiconductor substrate a distance greater than a length of each of the plurality of fins.

15. The device of claim 10, wherein the plurality of fins include a first plurality of fins within a first region of the semiconductor substrate and a second plurality of fins within a second region of the semiconductor substrate, wherein the cut opening is disposed within the second region of the semiconductor substrate.

16. A device comprising:

a plurality of fins disposed over a semiconductor substrate, the plurality of fins including source/drain regions and channel regions extending between the source/drain regions;

source/drain junctions disposed over the source/drain regions of the plurality of fins;

an interlayer dielectric disposed over the source/drain junctions;

a cut opening located between an adjacent pair of the source/drain junctions and extending into the semiconductor substrate;

a dielectric fill layer disposed within a bottom portion of the cut opening, wherein a top surface of the dielectric fill layer extends to or above a top surface of the fins and extends to a top surface of the source/drain junctions;

and

a functional gate stack disposed over each of the channel regions of the plurality of fins and within a top portion

of the cut opening over and contacting the top surface of the dielectric fill layer, wherein a pair of opposing edges of the dielectric fill layer within the top portion of the cut opening are aligned with and contact edges of one of the adjacent pair of the source/drain junctions. 5

17. The device of claim 16, wherein the functional gate stack within the top portion of the cut opening directly overlies the dielectric fill layer within the bottom portion of the cut opening.

18. The device of claim 16, wherein the pair of opposing edges are oriented perpendicular to a length direction of at least one of the plurality of fins. 10

19. The device of claim 16, further comprising a silicon nitride spacer layer disposed over sidewalls of the interlayer dielectric. 15

20. The device of claim 16, wherein the plurality of fins include a first plurality of fins within a first region of the semiconductor substrate and a second plurality of fins within a second region of the substrate, wherein the cut opening is disposed within the second region of the semiconductor substrate. 20

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